



*The Abdus Salam
International Centre for Theoretical Physics*



1938-12

Workshop on Nanoscience for Solar Energy Conversion

27 - 29 October 2008

**Solid-State Dye-Sensitized Solar Cells: Device Operation, Optimization, Charge
Generation Mechanism and Novel Electrodes Structured from Diblock Copolymers**

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Understanding loss
mechanisms in solid-
state dye-sensitized
solar cells and diblock
copolymer templated
mesostructured
electrodes

Henry J. Snaith

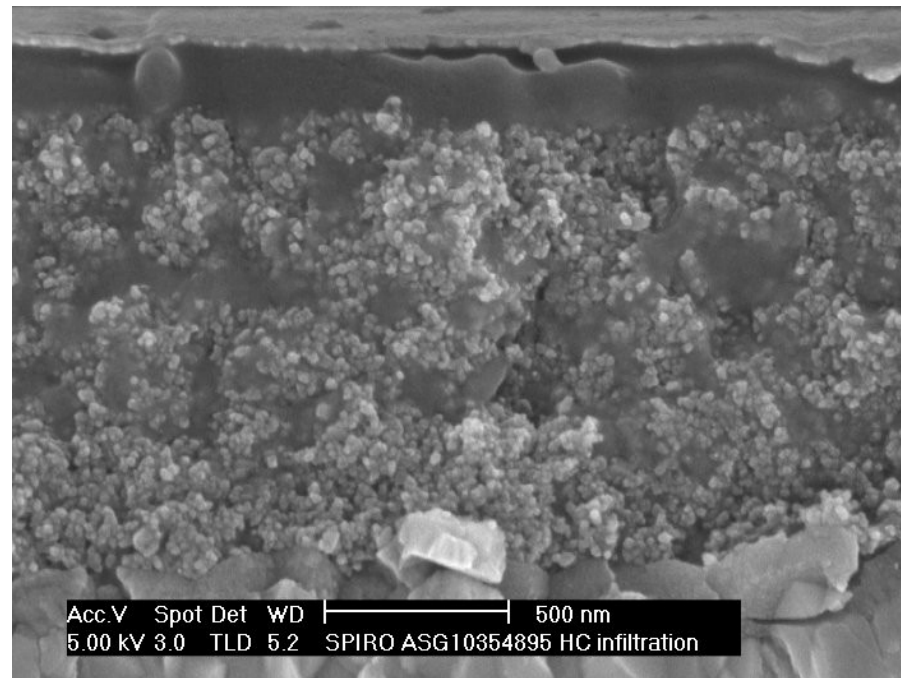
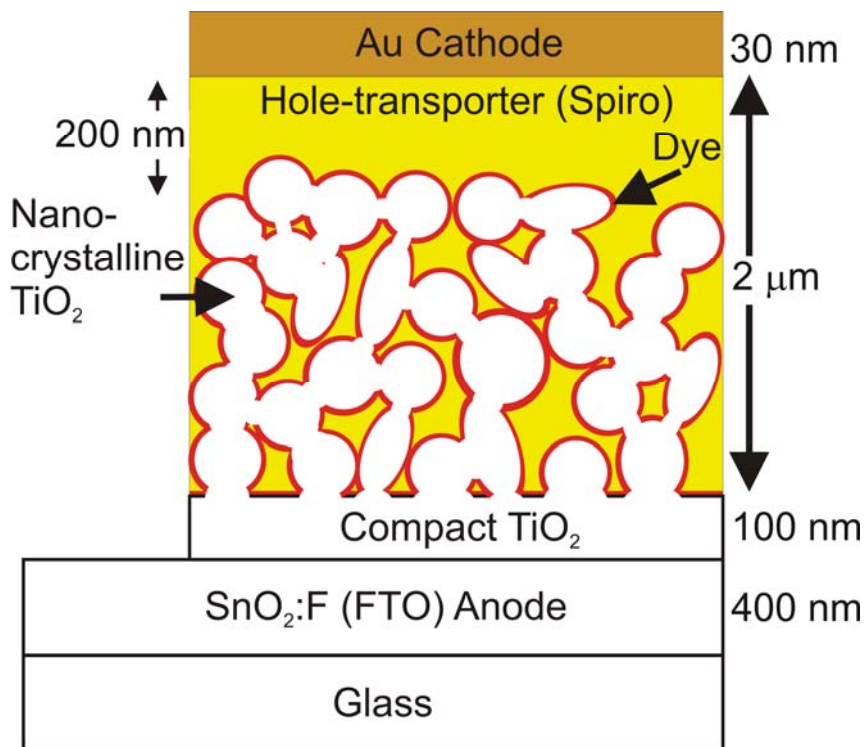
Trieste, 28th October 2008

h.snaith1@physics.ox.ac.uk

Overview

- Probing the loss mechanisms in solid-state DSCs: current collection and pore filling
- Probing the electron transport in mesoporous TiO_2
- TiO_2 electrodes structured by diblock copolymers templates: probing the structure-function relationship

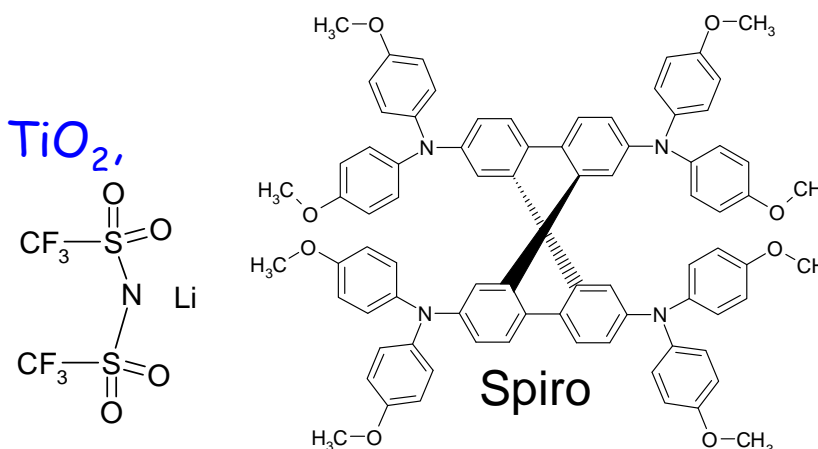
Solid-state dye-sensitized solar cell*



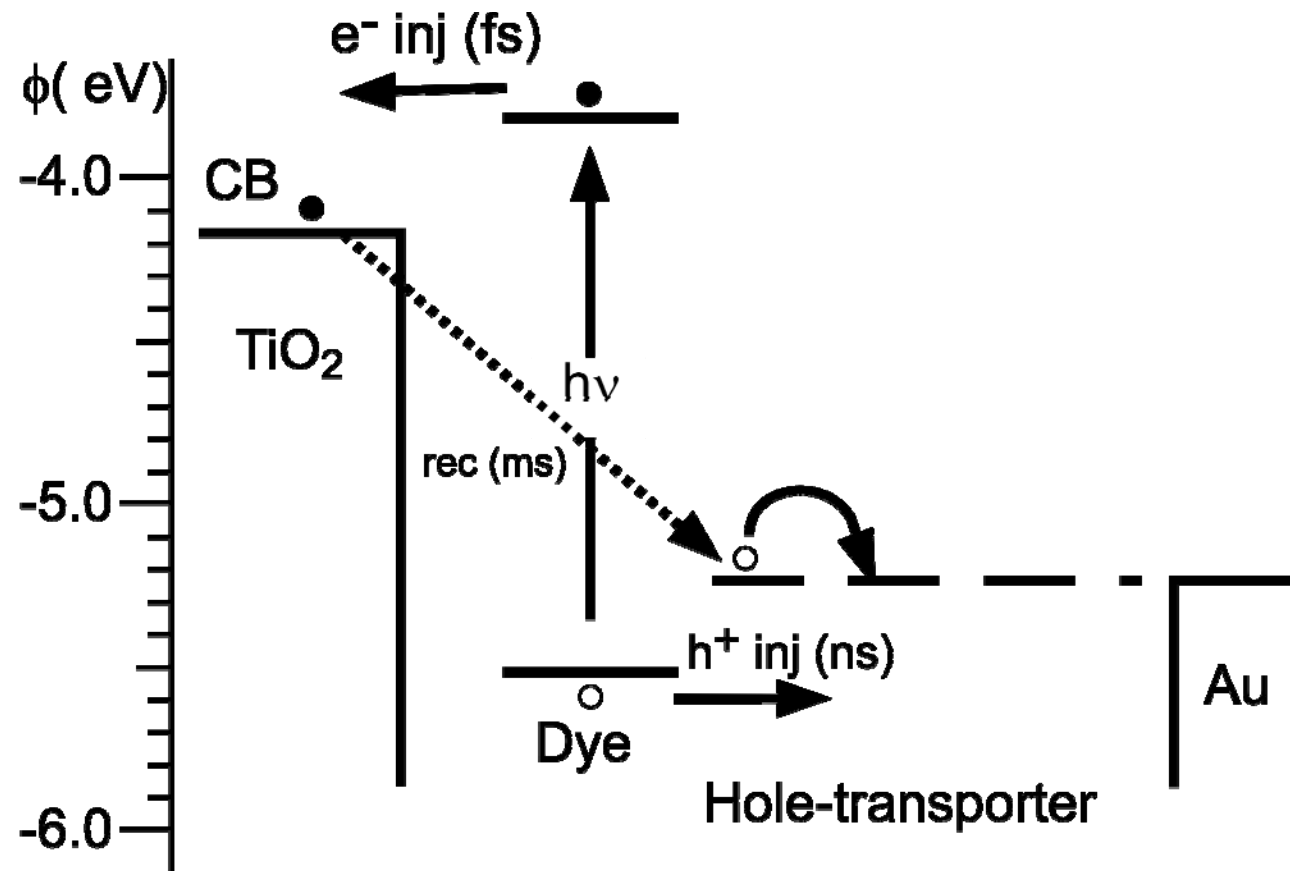
Light absorption in dye, electron transfer to TiO_2 , hole transfer to Spiro-OMeTAD.

Additives in HTM: tbp and Lithium TFSI

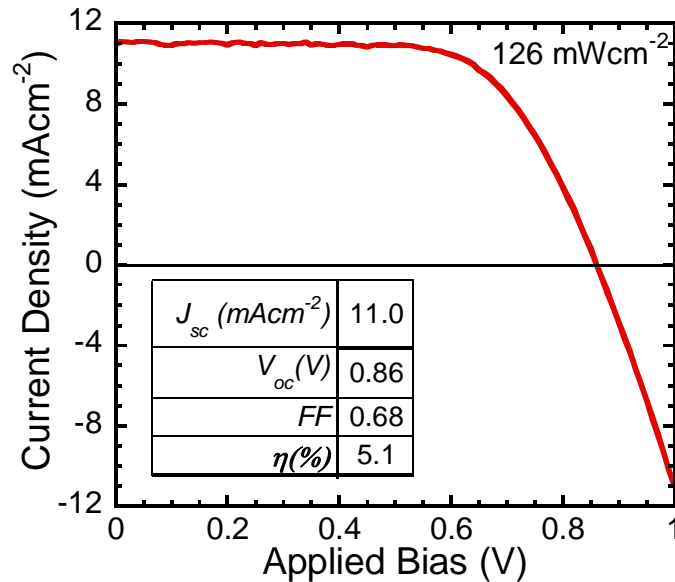
*Bach, U. et al. Nature 395, 583–585 (1998)



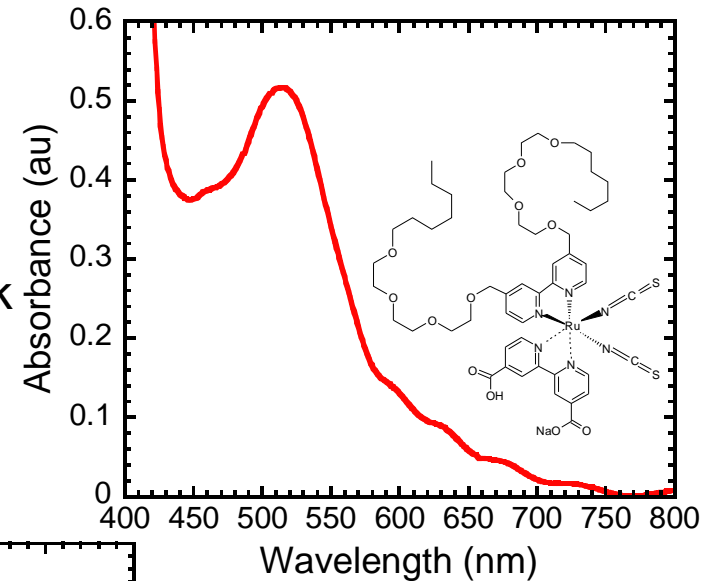
Solid-state DSC operation



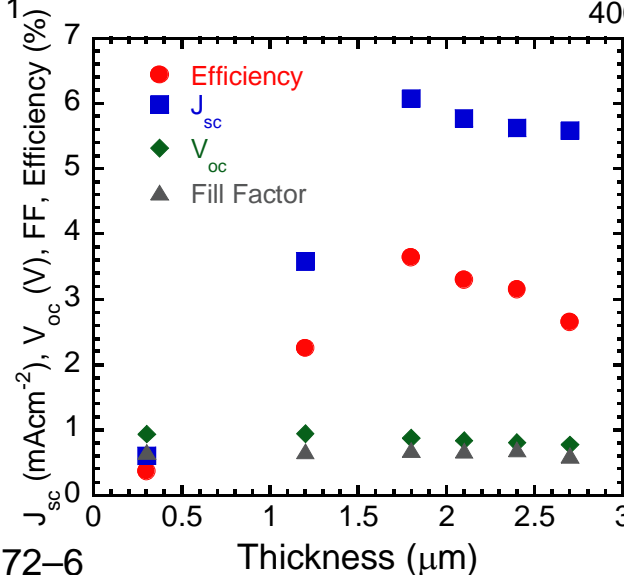
Solar Cell performance



Maximum solar cell performance when only 2 μm thick



Only 70% light absorbed At peak wavelength



Generate 6 to 9 mA/cm^{-2} out of possible 23 mA/cm^{-2}

H. J. Snaith et al. Nano. Lett. 2007 7 3372–6

H. J. Snaith et al. Adv. Matter. 2007 19 3187–200

Possible losses

Electronic-

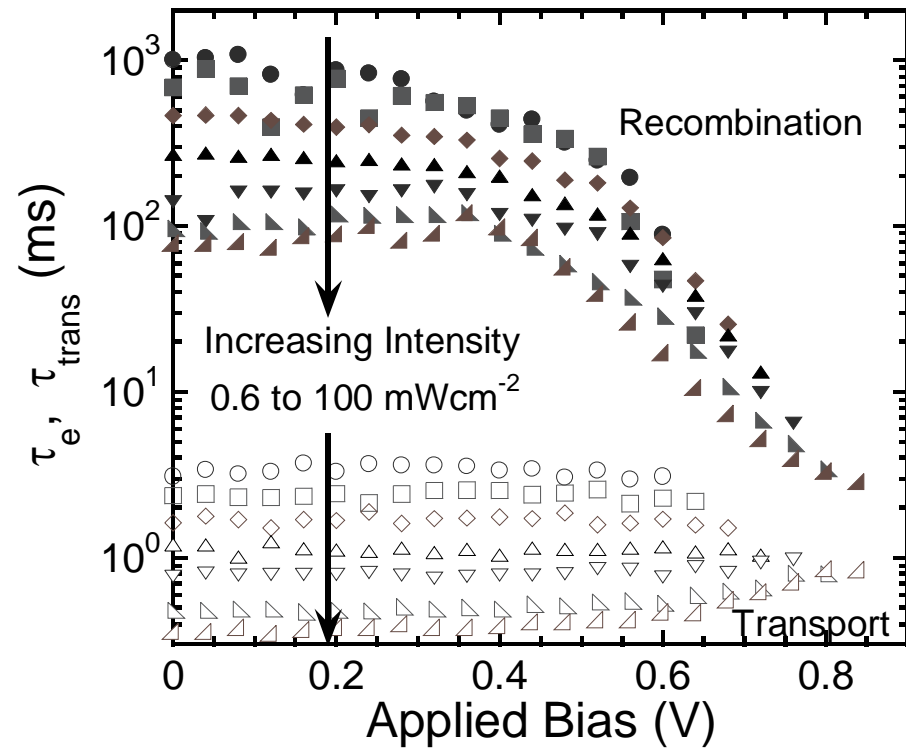
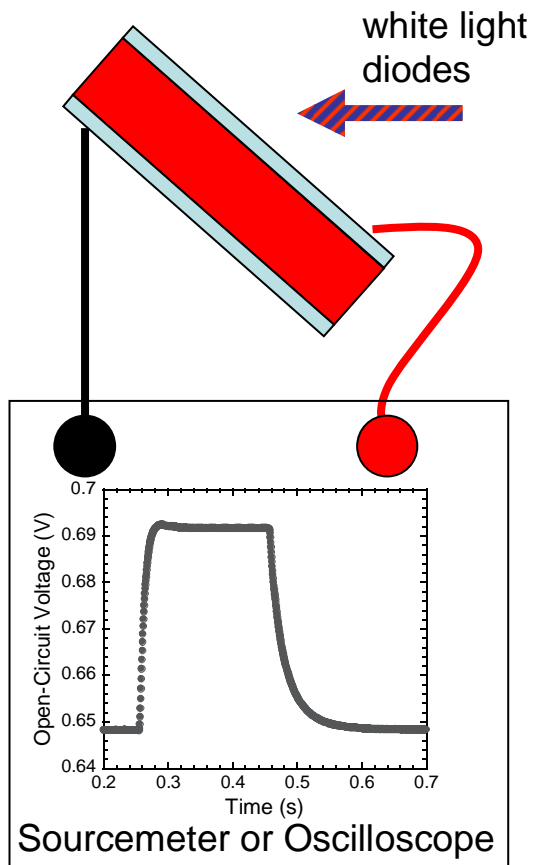
- Recombination (bi-molecular)
- Poor charge generation
 - Electron injection
 - Hole-transfer
 - Electron hole separation

Physical-

- Ineffective pore infiltration with spiro-OMeTAD

Transport and recombination

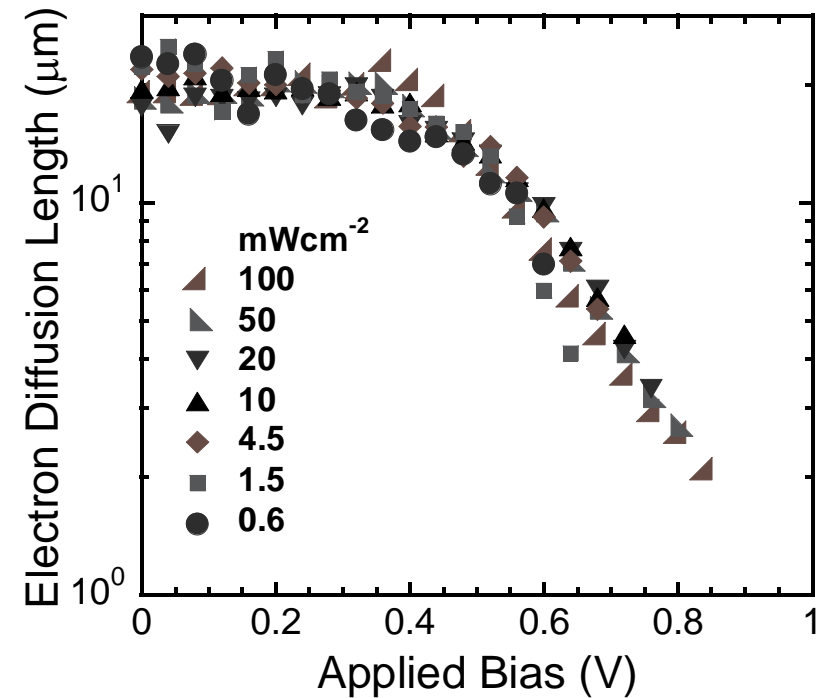
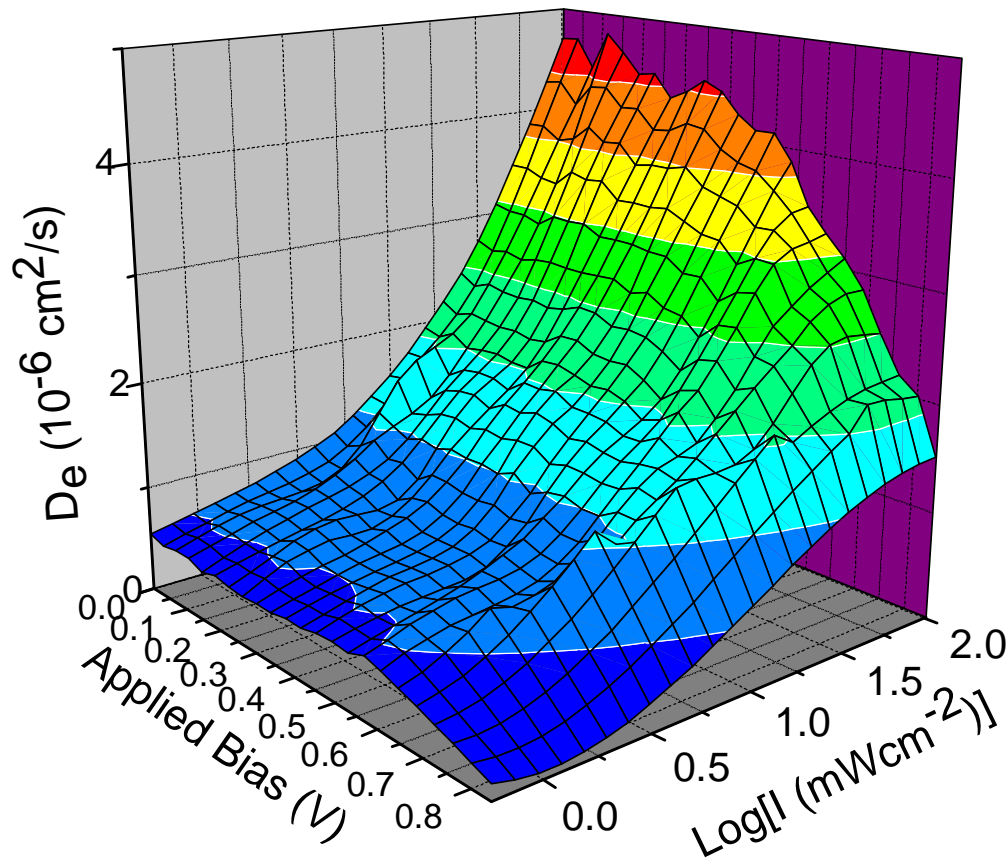
Red light diodes
20 ns rise/fall
time 1ms pulse
width.



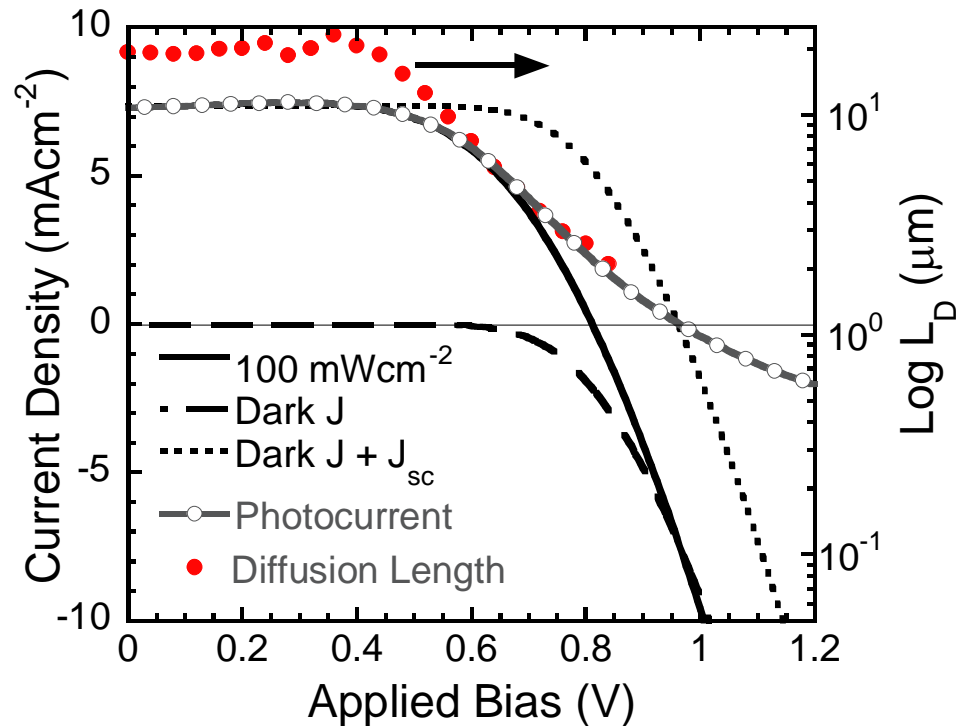
Transport and recombination

$$D_e \sim d^2 / 2.35 \tau_{trans}$$

$$L_D \approx \sqrt{D_e \tau_e}$$

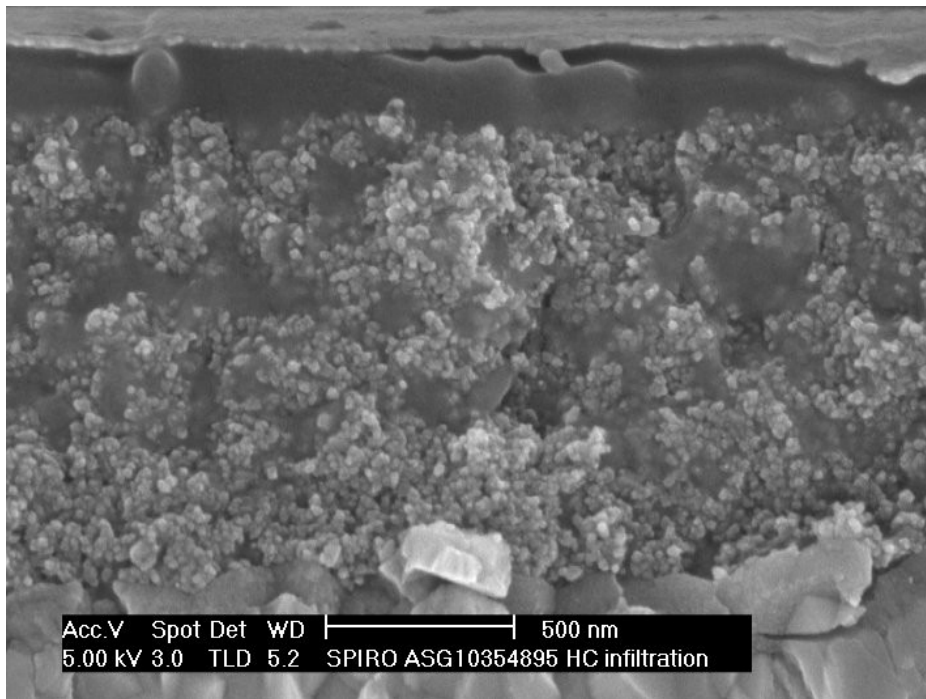


Collection Limiting Photocurrent

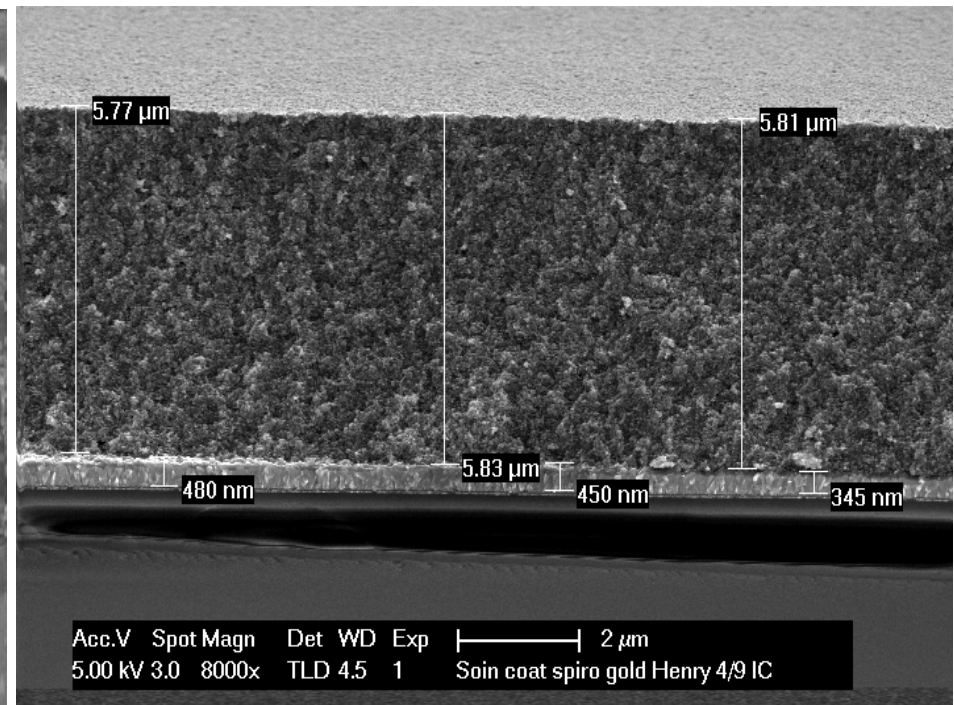


- Loose PC from $\sim 0.5 \text{ V}$
- Coincides well with drop in L_d
- No influence near J_{sc}
- η goes from 4 to 5% if all short-circuit PC collected up to 1 V

SEM images: pore-filling

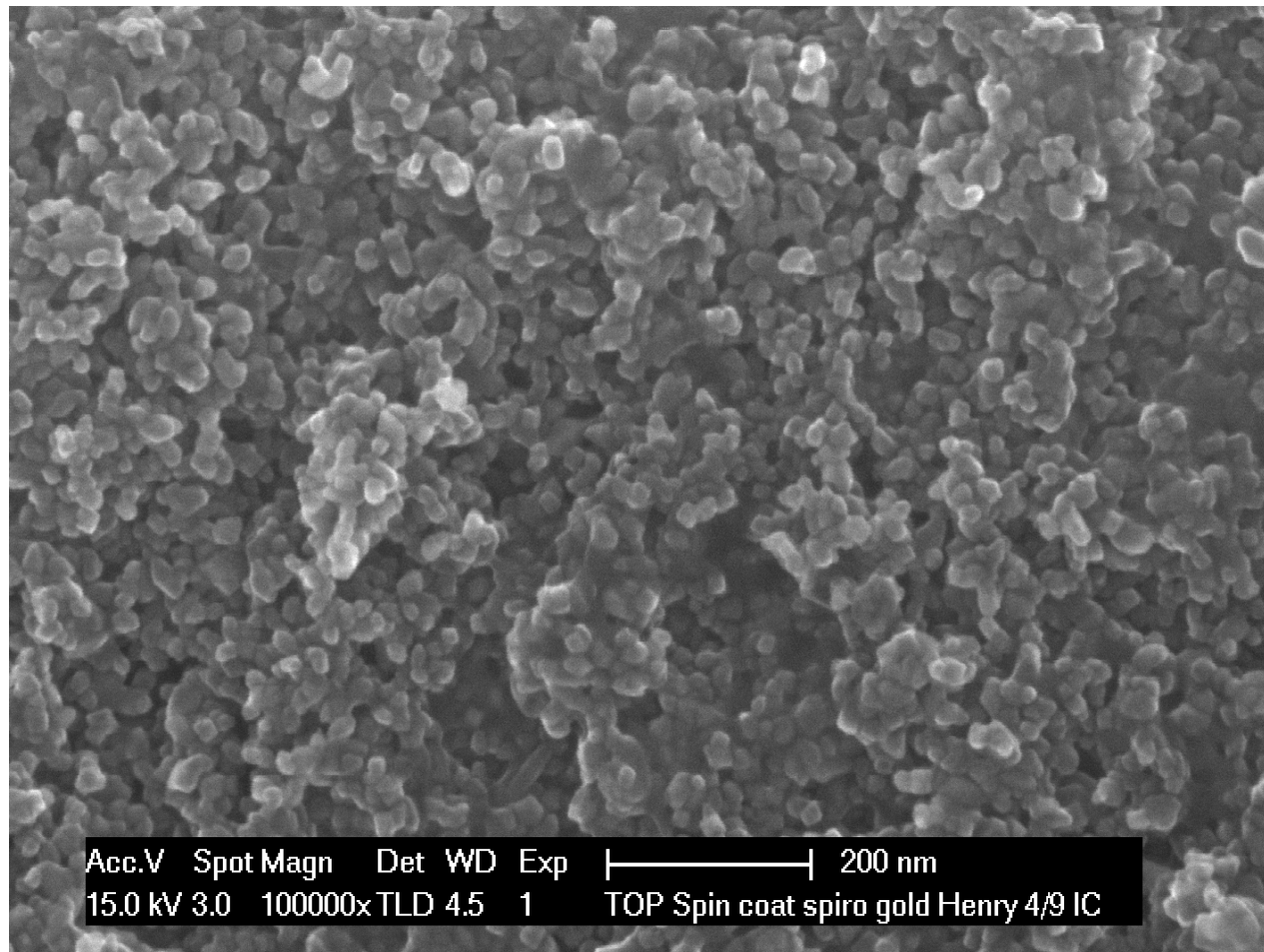


2 μm thick film

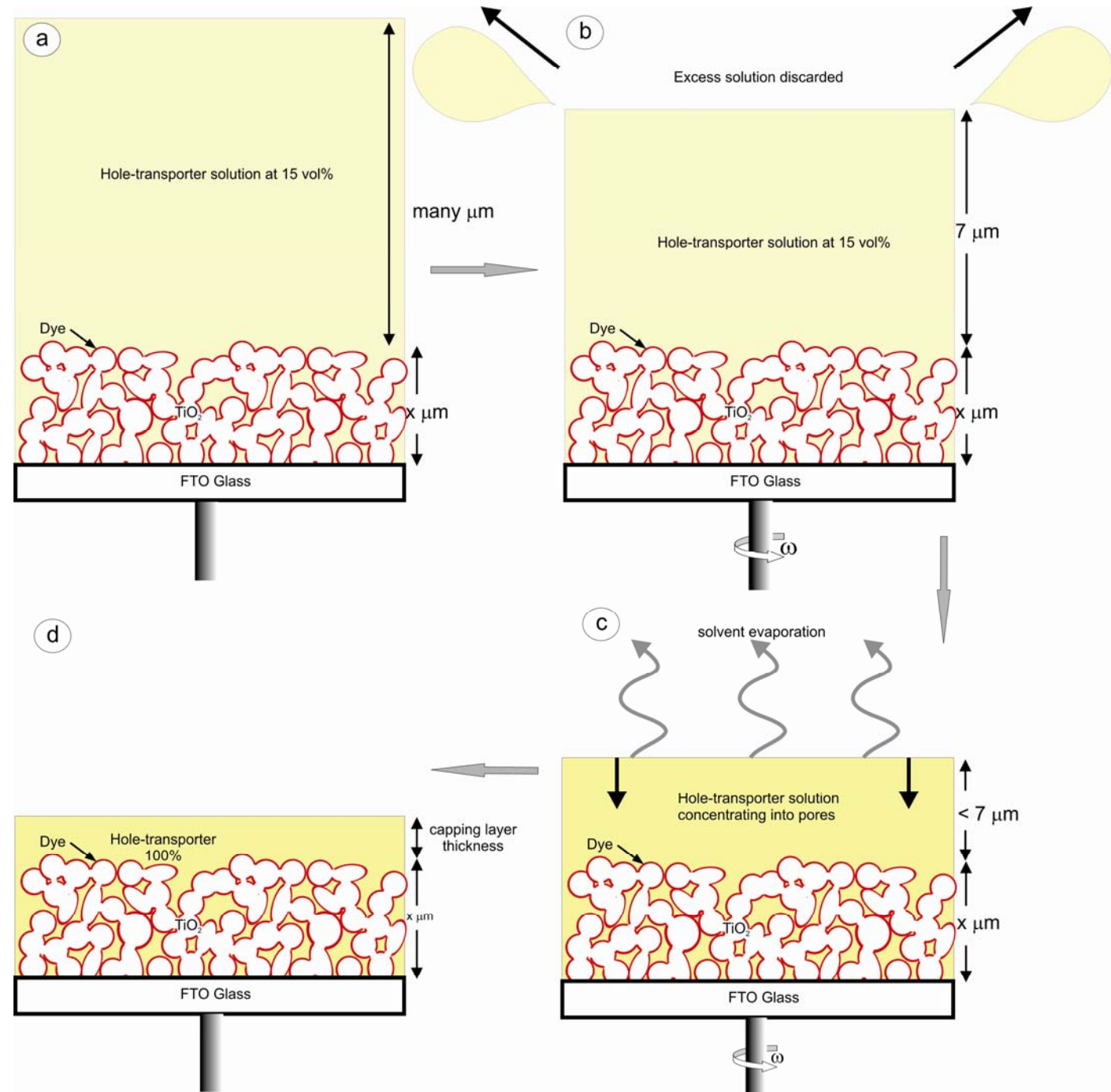


6 μm thick film

SEM images: pore-filling



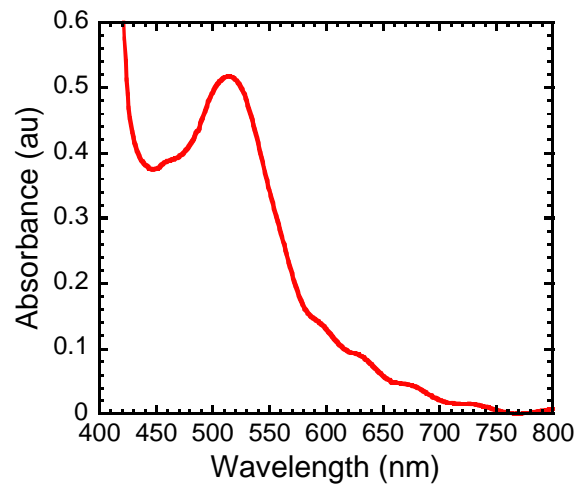
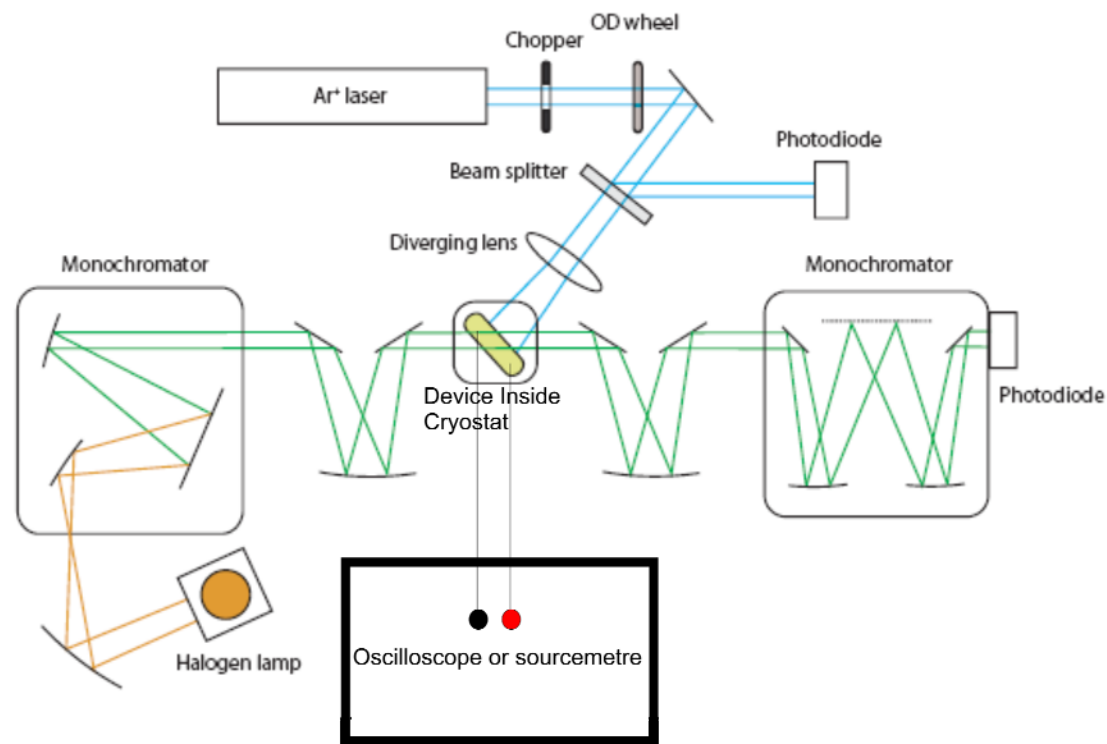
Spin-coating process



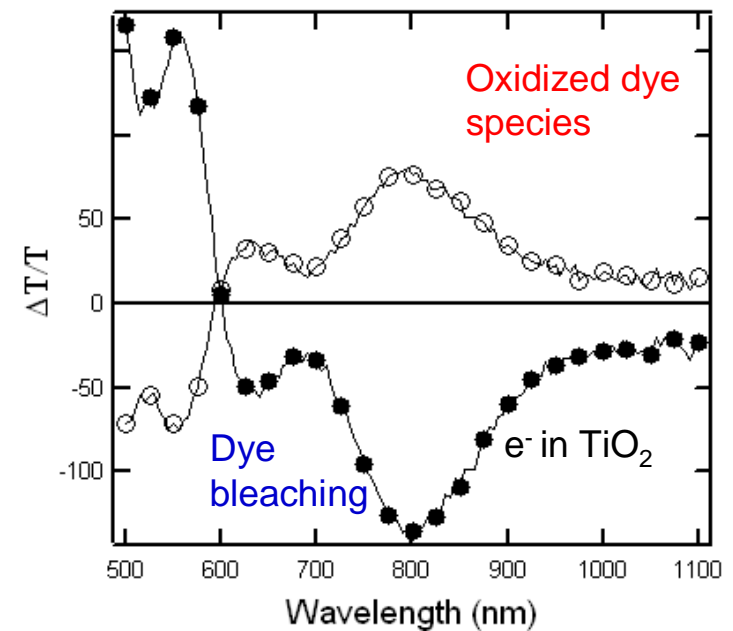
Quantifying pore filling

- $t_{spiro} = \text{Sol. Conc.} \times (\text{wet over layer thickness} + (\text{porosity} \times \text{TiO}_2 \text{ thickness}))$
– capping layer thickness
 - Pore filling fraction = $t_{spiro} / (\text{porosity} \times \text{TiO}_2 \text{ thickness})$.
- 0.85 for thin films of 1.8 μm
- 0.4 for 6 μm thick films

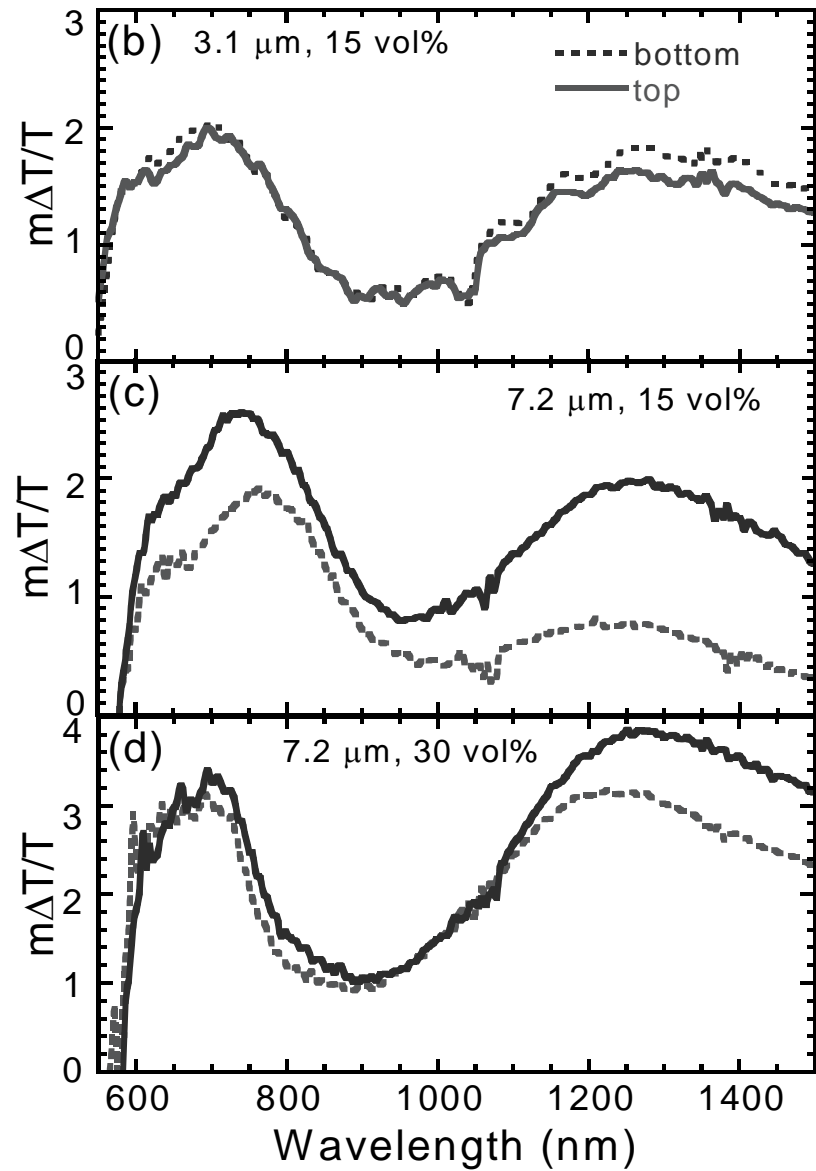
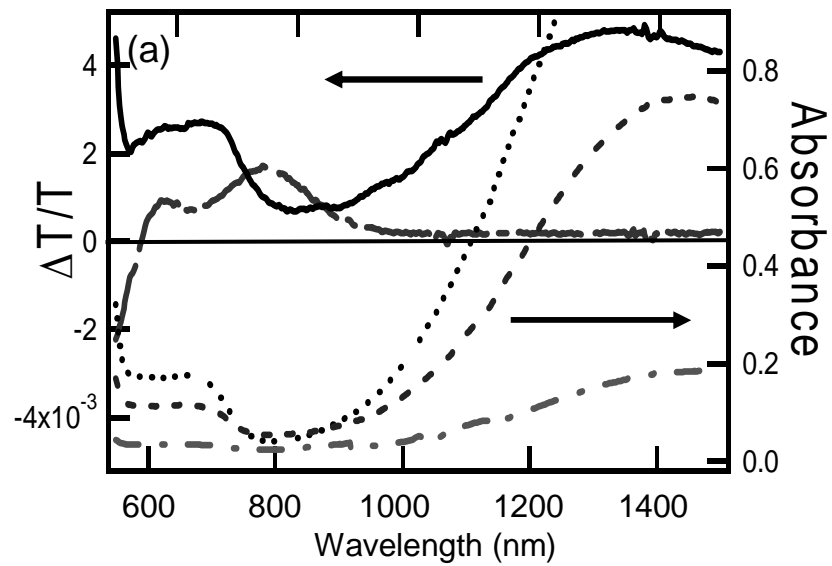
Photoinduced absorption



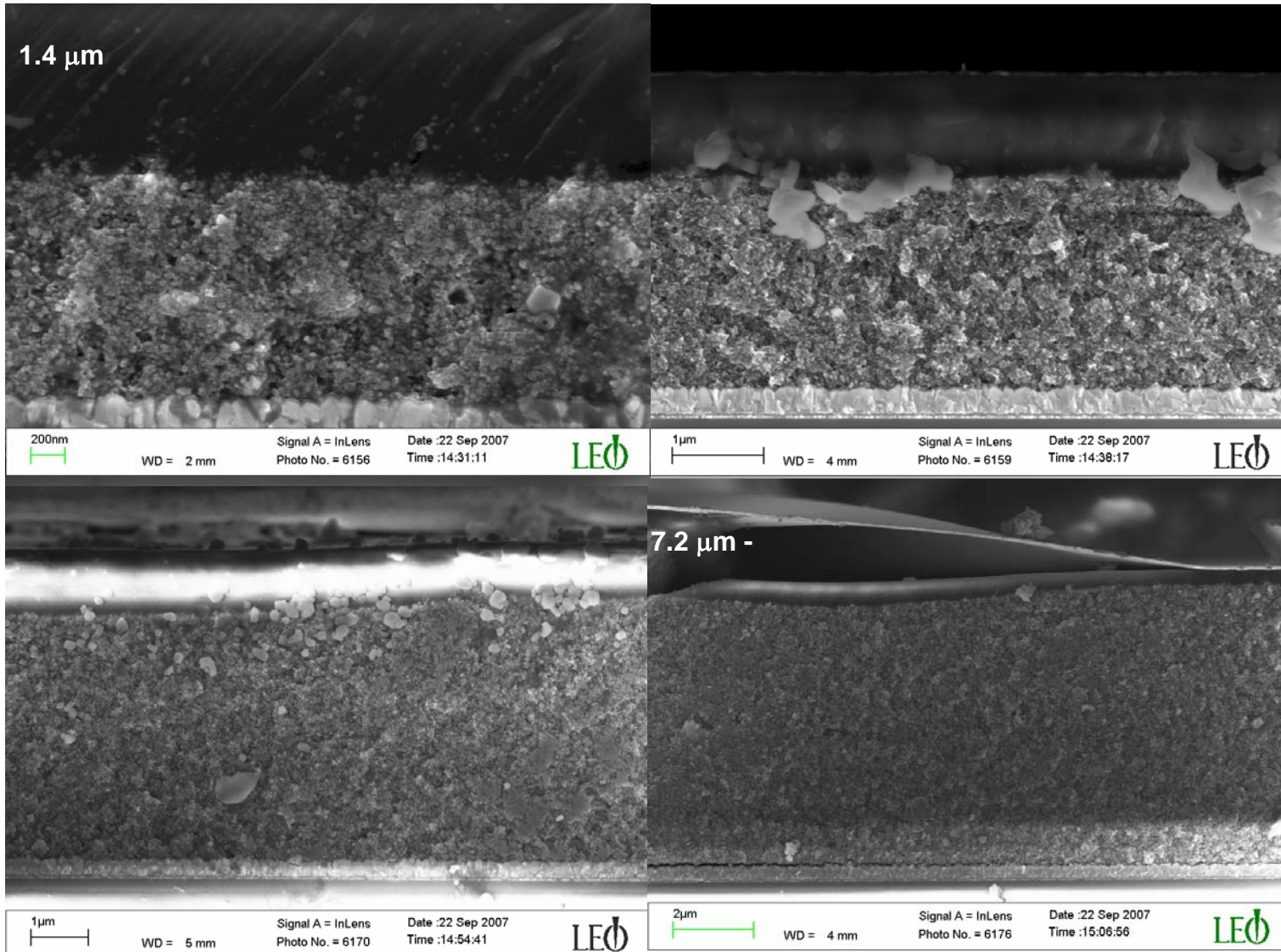
Typical PIA signal



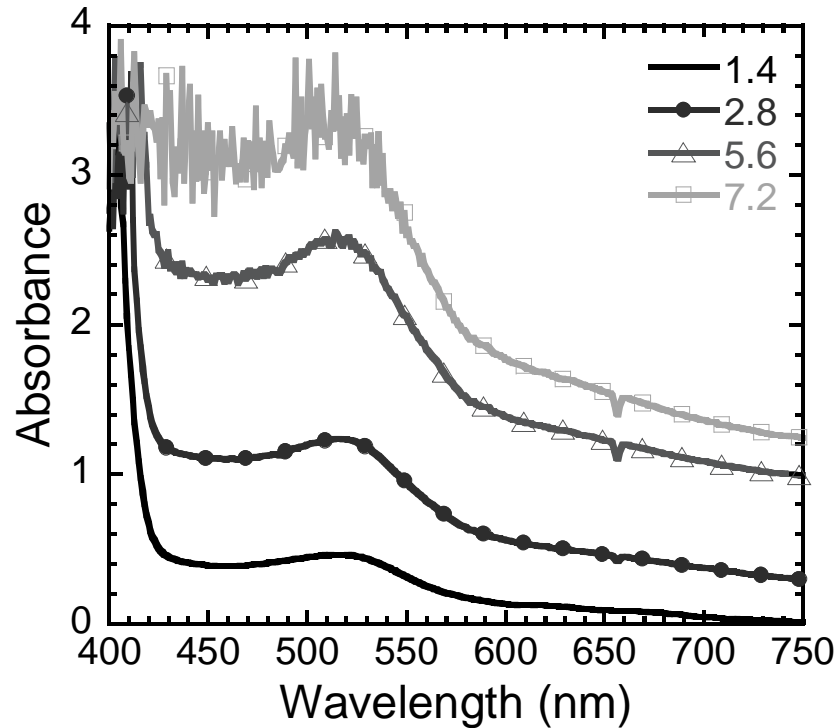
PIA on Devices



Pore filling with 30 wt%

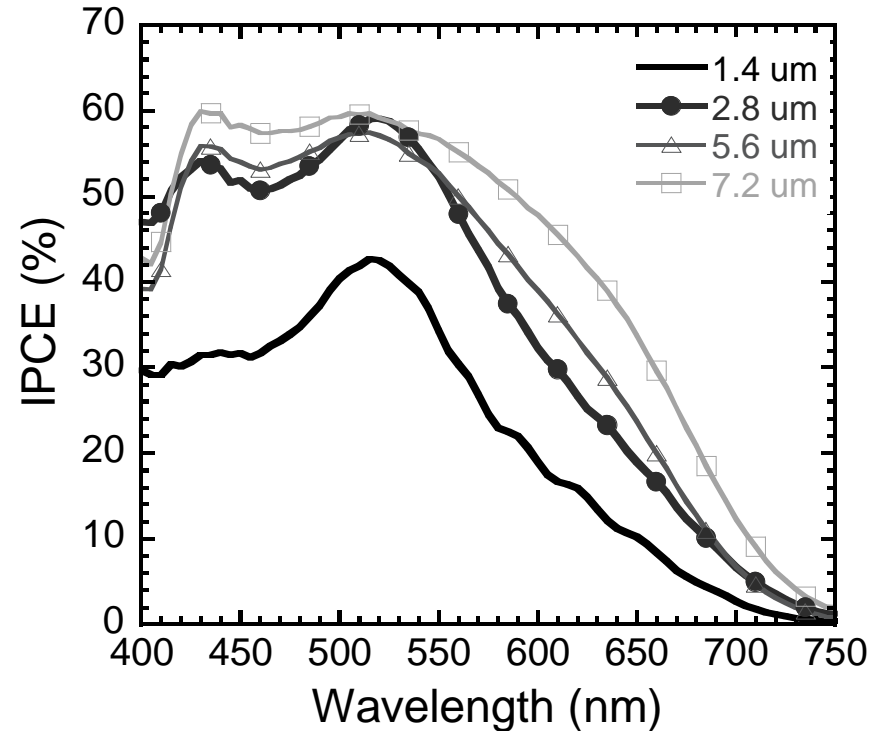


Charge collection through thick films



IQE ~ 70 to 75%

Where has the
other 25 to 30%
gone?



Electron injection?

Hole-transfer?

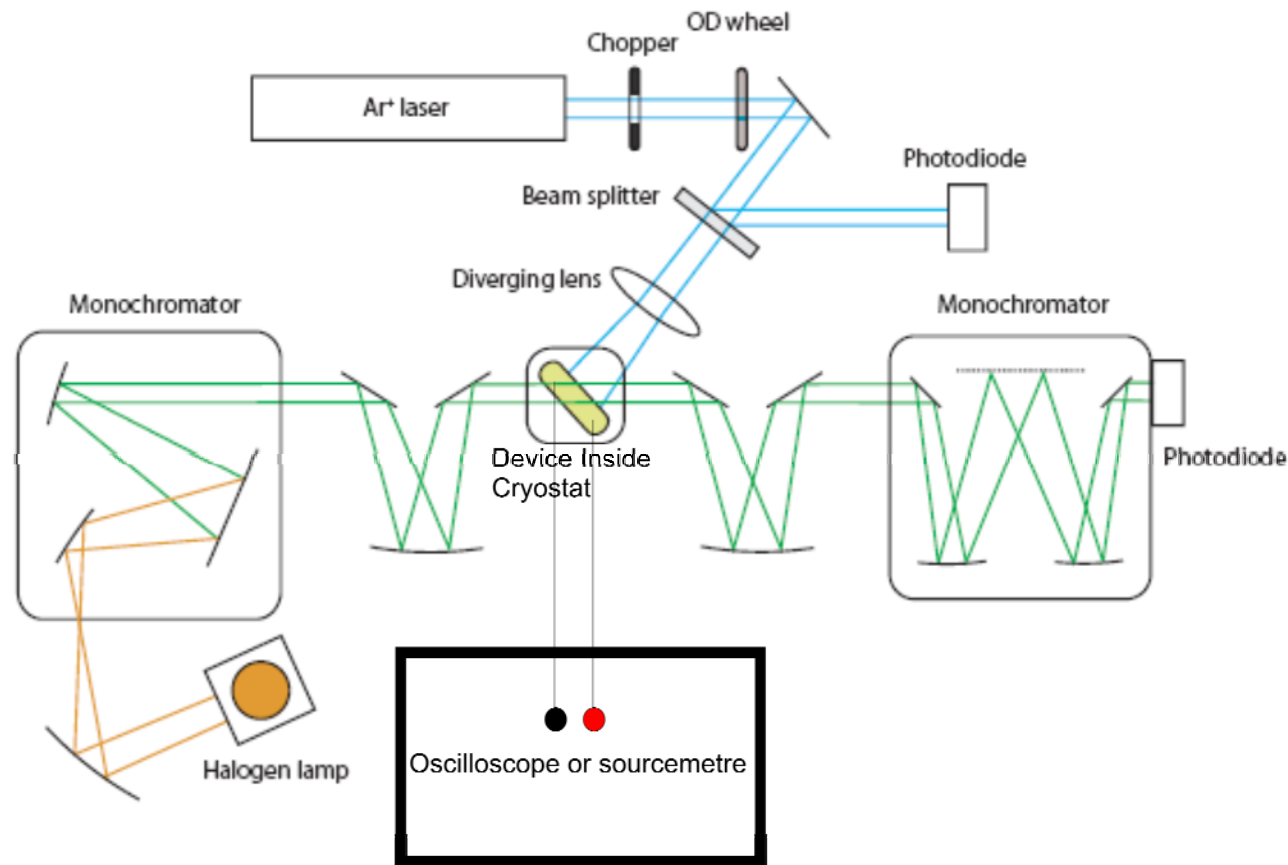
Charge separation?

Light absorption in oxidized
spiro-MeOTAD?

II

Probing the electron
transport in mesoporous
 TiO_2

"Photo-induced charge-conductivity modulation spectroscopy"



Device structure

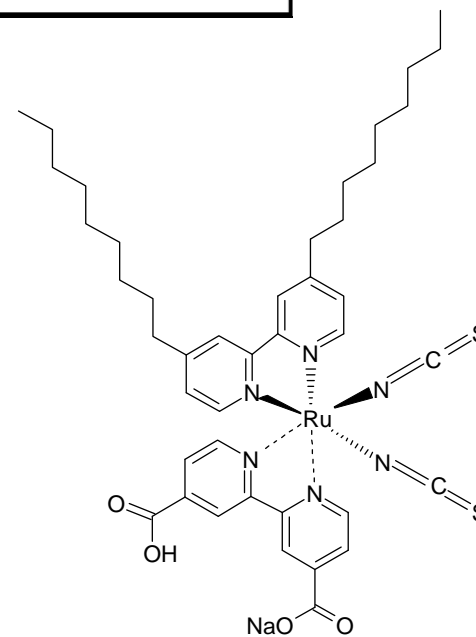
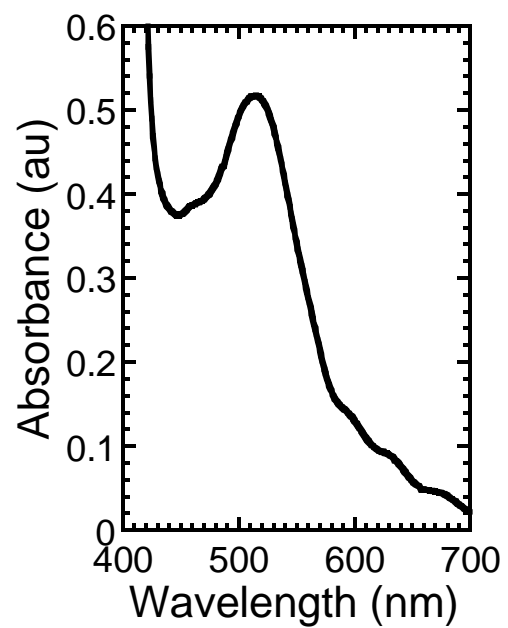
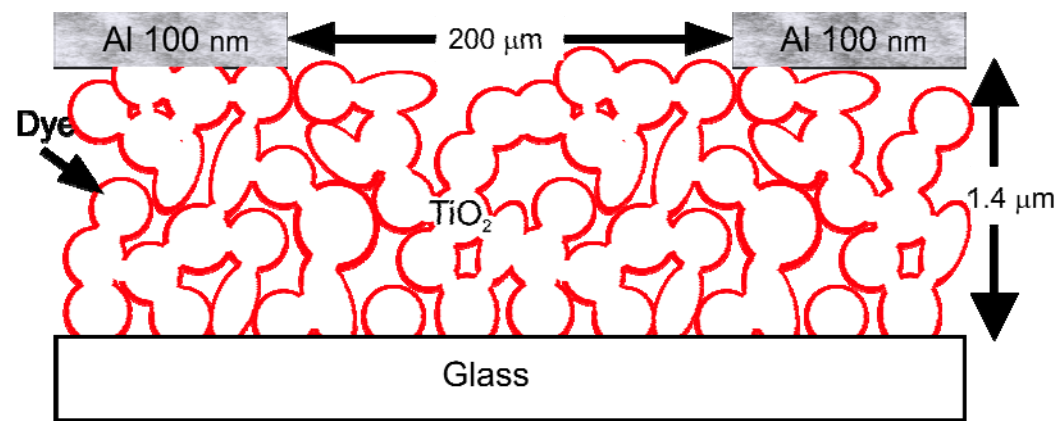
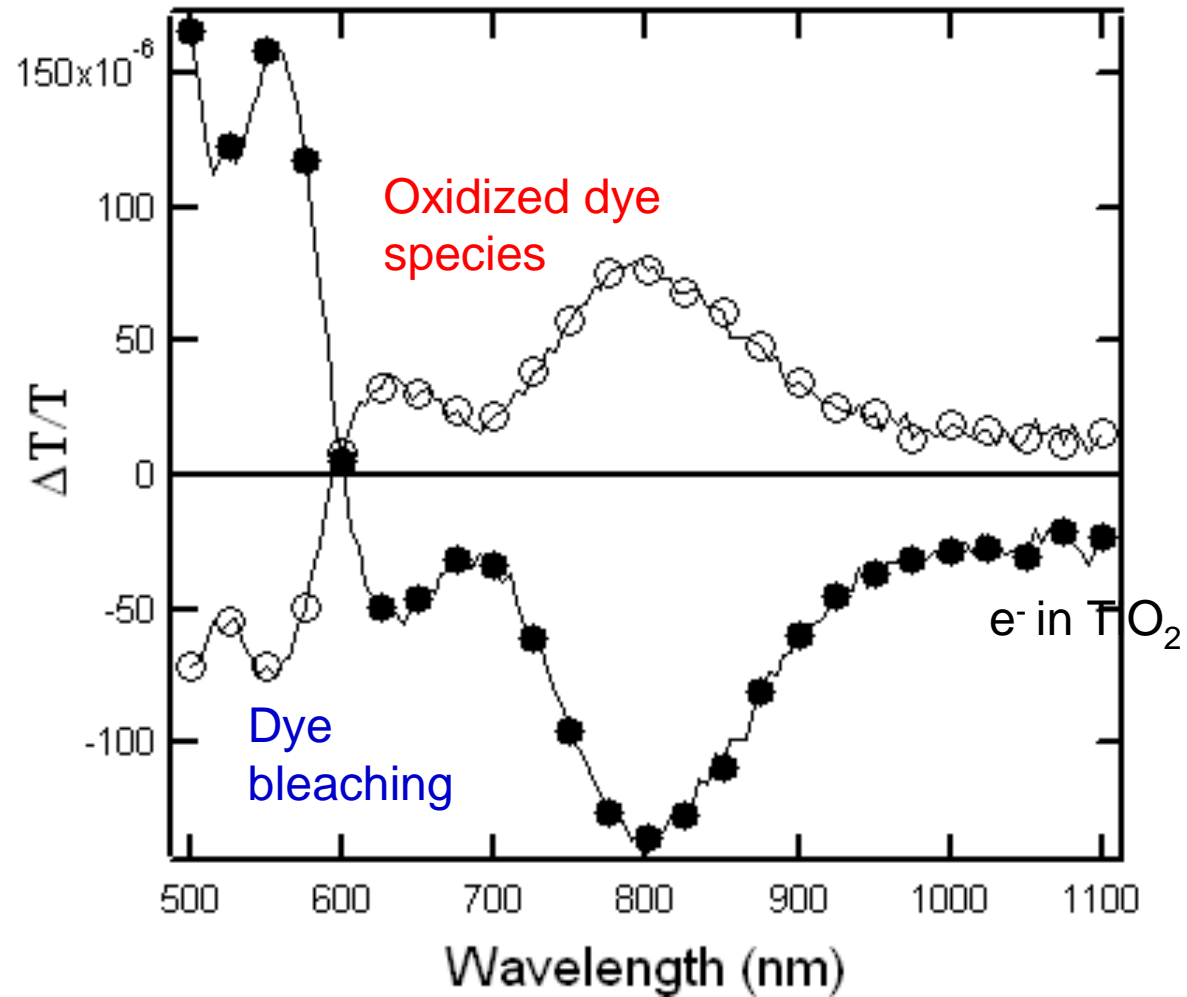
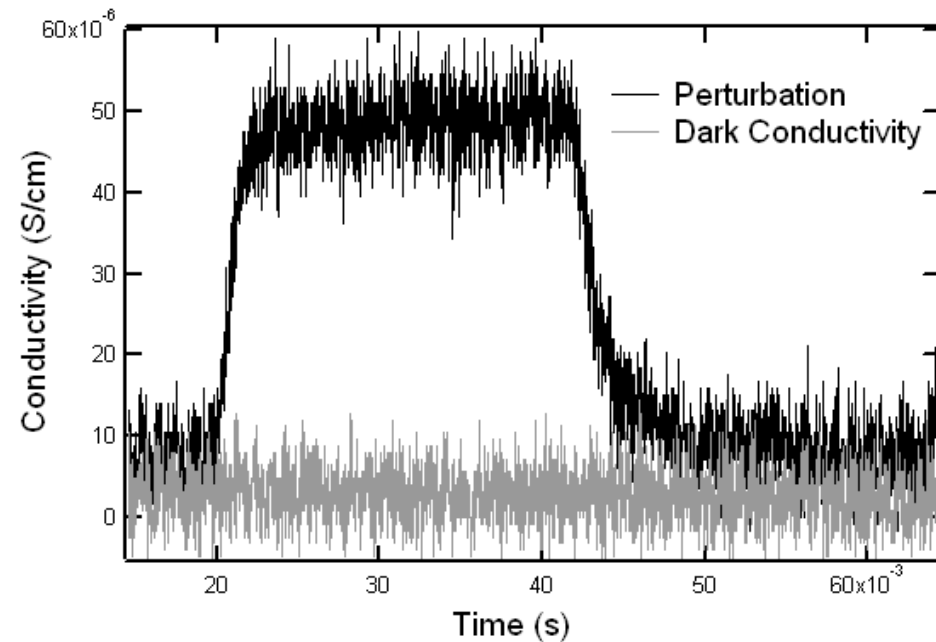
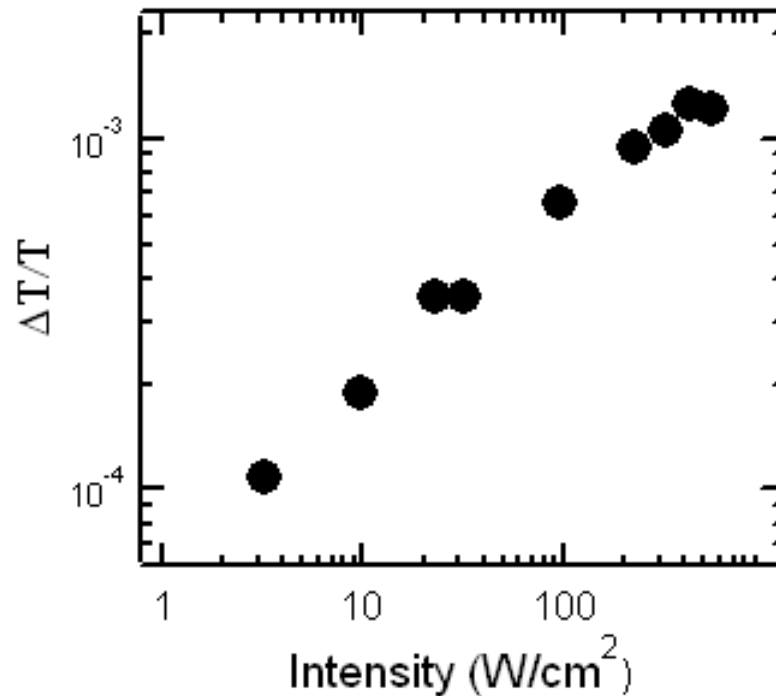


Photo-induced absorption signal



PIA signal and conductivity response



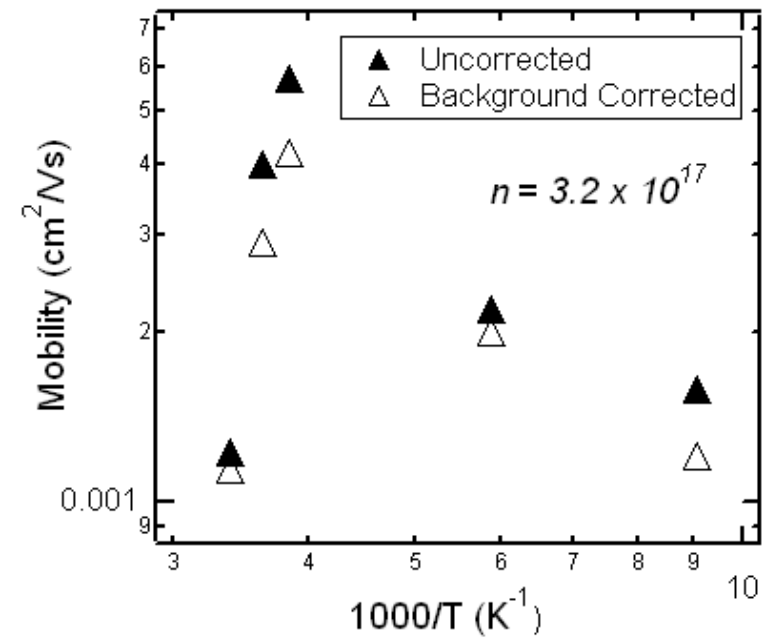
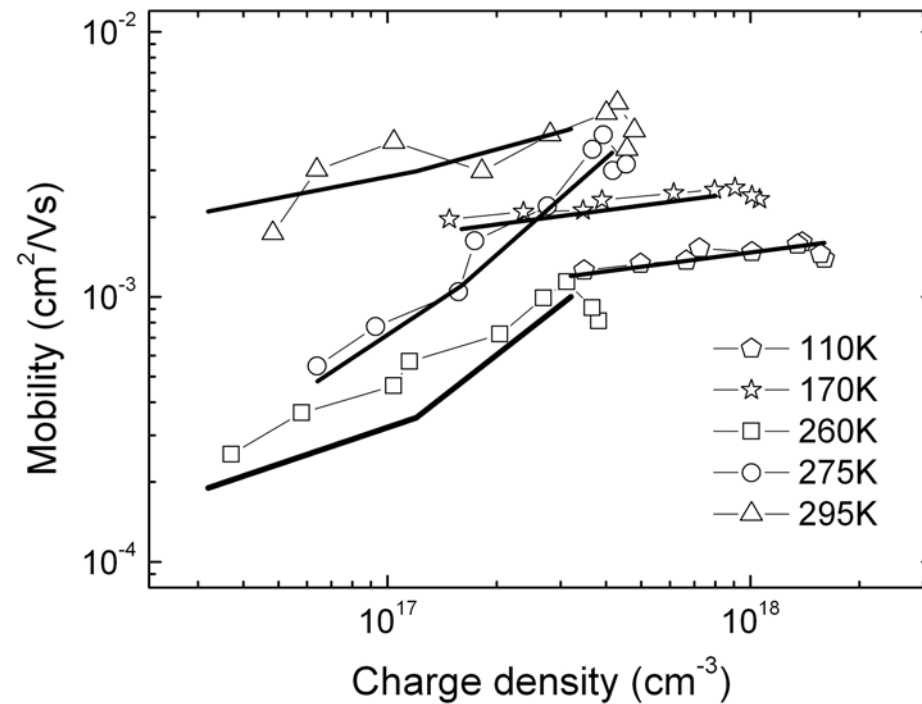
$$\Delta OD = -\text{Log} \left[1 + \frac{\Delta T}{T} \right]$$

$$n_{\text{dye}} (\text{cm}^{-3}) = \frac{N_a A}{1000 \epsilon \times d}$$

$$\Delta \sigma = \frac{IL}{Vwt} = \frac{\Delta V_{os} L}{rVwt}$$

$$\sigma = \mu \times n \times e$$

Mobility data



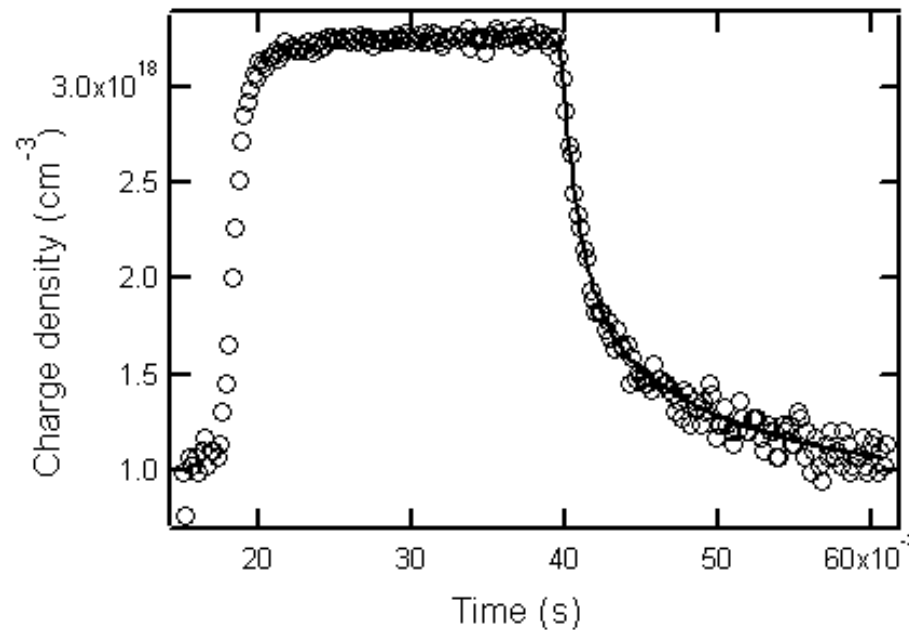
Funny temperature dependence
little charge density dependence at low temperature

Extracting charge recombination

$$\sigma = \mu \times n \times e$$

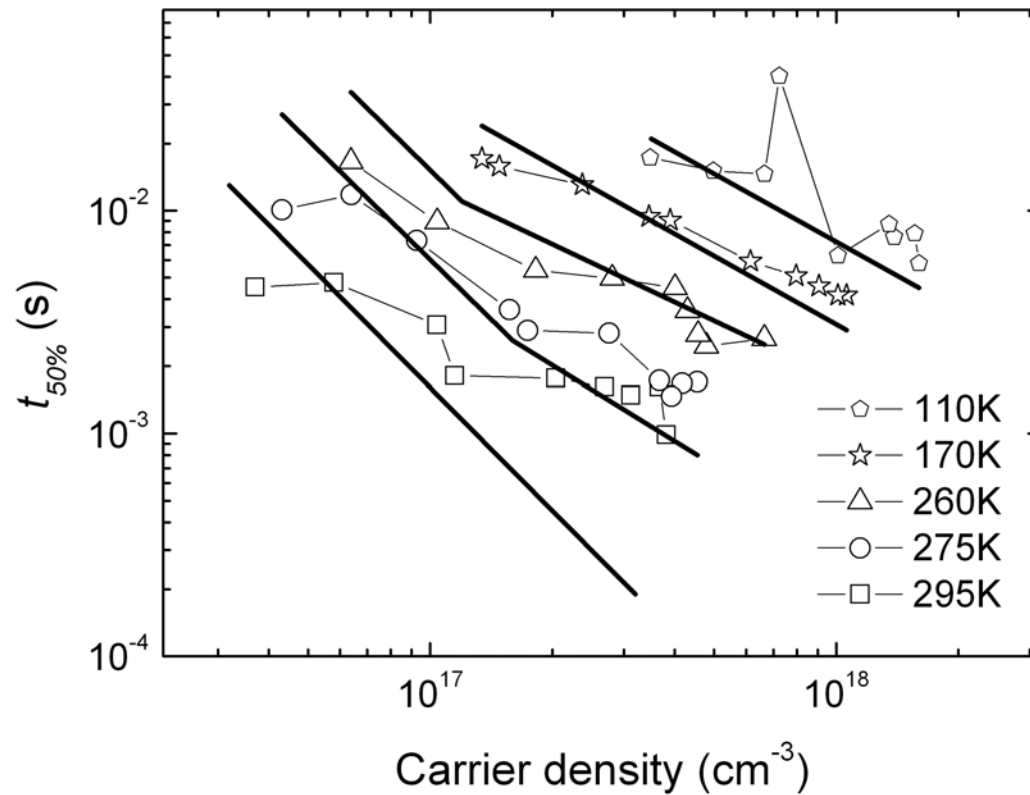
If mobility was constant we could just take the conductivity $t_{50\%}$ to $= n t_{50\%}$
However, it is not.....

We know $\sigma(t)$ and we know $\sigma(n)$
therefore extract $n(t) \rightarrow$



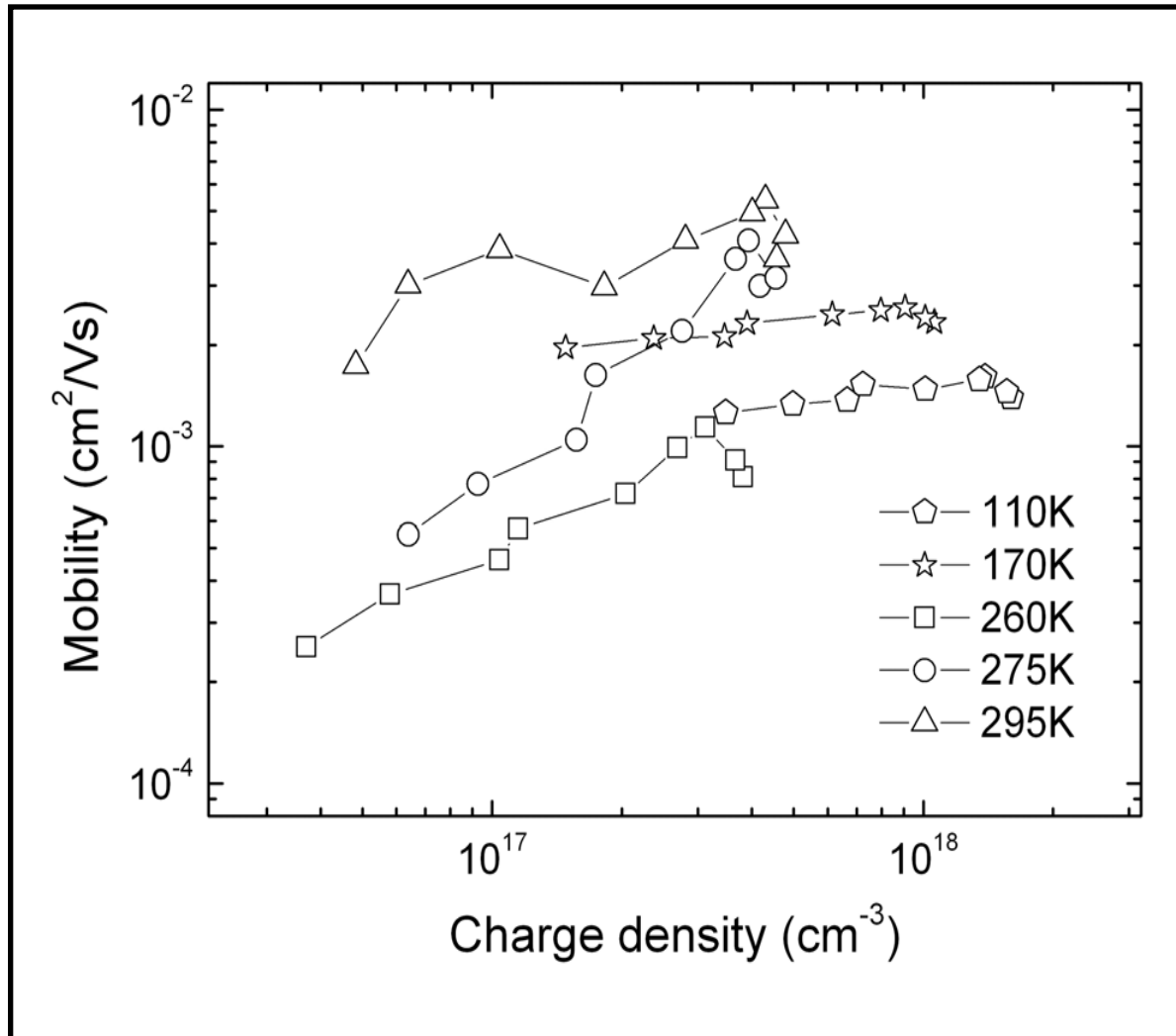
$$n(t) = K \exp\left(-\left(\frac{t}{\tau}\right)^\alpha\right)$$

Recombination results



$t_{50\%}$ monotonically:
reduces with increasing temperature
reduces with increasing charge density

The transport data



General trends

- Charge density dependence of mobility (indicative of trap filling effects)
- Charge density dependence falls with reducing temperature
- Mobility rises with falling temperature to begin with (up to 260K), and thereafter falls

What could be going on?

- Mobility increasing as temperature falls implies the DoS may be becoming shallower
- The charge density dependence is also a function of the DoS, and this changes with temperature as well

Try fitting to the data while allowing the DoS to vary with temperature

(as it turns out other transport [1] and non-transport based [2] studies also make this assumption)

[1] Anta *et al.*, *J Phys. Chem. C.*, **111** (37), pp. 13997-14000 (2007).

[2] Abayev *et al.*, *J. Solid State Electrochem.*, **11**, pp. 647-653 (2007).

Why might the DoS change with temperature?

- Lots of things that cause traps
 - e.g. crystal structure, degree of protonation, chemical impurities...or affect their depth
 - e.g. dielectric constant...that change with temperature
- A few people are confident they know what may cause a change in the DoS [2], but we're not amongst them

Developing a model I

- Here we calculate the de-trapping time based upon the trap energy

$$t_{i \rightarrow j} = -\ln(r) t_0 \exp(E_i / kT)$$

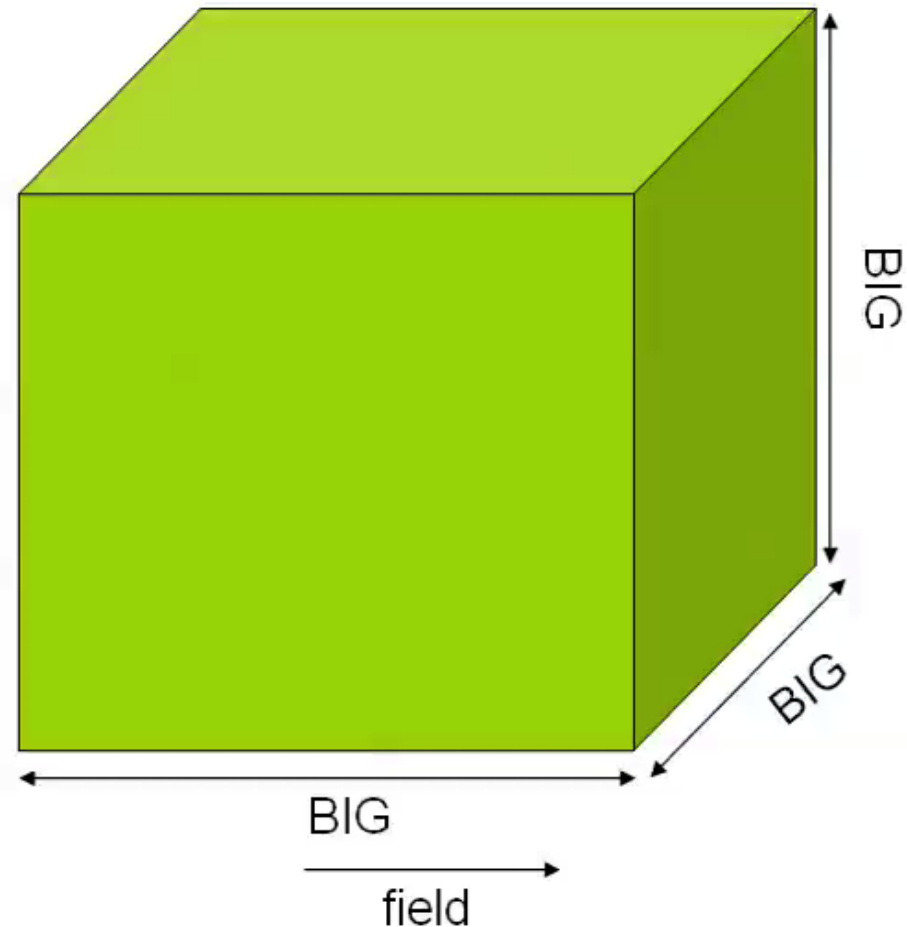
- The de-trapped carrier then moves with a velocity that has an isotropic (diffusive) and anisotropic (drift) part that is proportional to the field. Transition probability is then...

$$p(i \rightarrow j) = \frac{1}{6} + C \overline{u_{i \rightarrow j}} \cdot \overline{F}$$

- This approach is actually quite similar to the original MT model [3]

Developing a model II

- We take a simulation volume
- Divide it into individual traps spaced by 2nm
- Fill the volume up with an appropriate number of carriers for the charge density to work out the mobility
- Carriers then execute a biased random walk as determined by the equations shown previously
- Repeated many times for many different conformations of trap energy
- Choose parameters to be the same as used in other models where possible
 - $\tau_0 = 2 \times 10^{12} \text{ s}^{-1}$
 - $F = 1.5 \times 10^4 \text{ V/m}$
 - and to be sensible elsewhere
 - $C = 10^{-6}$
- The DoS is allowed to vary

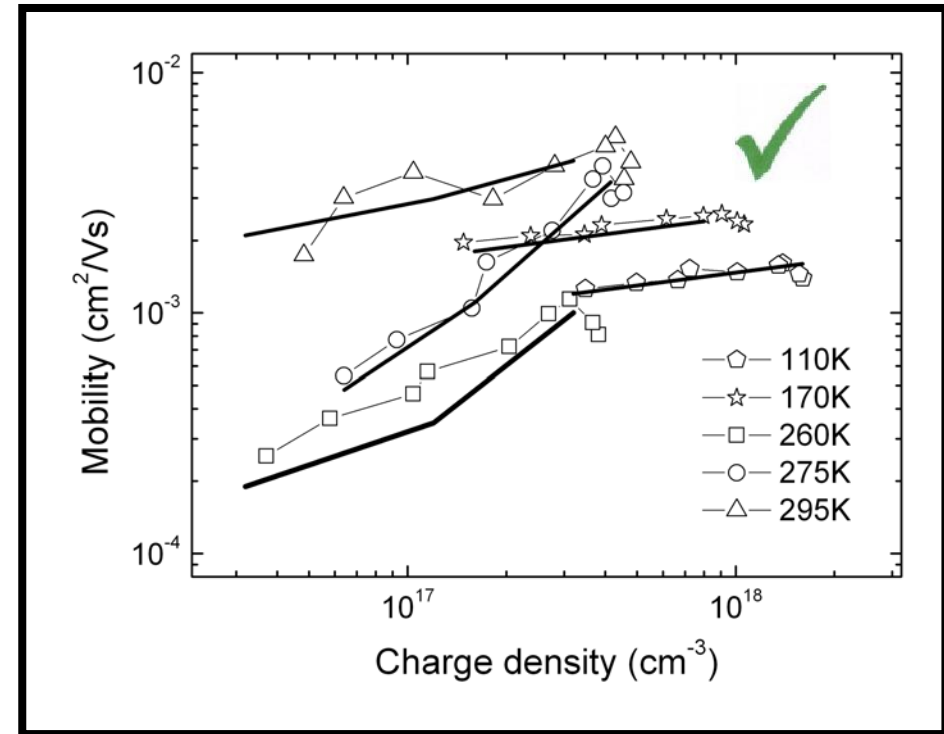


movie

Mobility fits to the data

Remarkably little flexibility to fit to the charge density curves...

- Hopping model didn't work
- Other multiple trapping models didn't work
- Gaussian and exponential DoS could not be used interchangeably

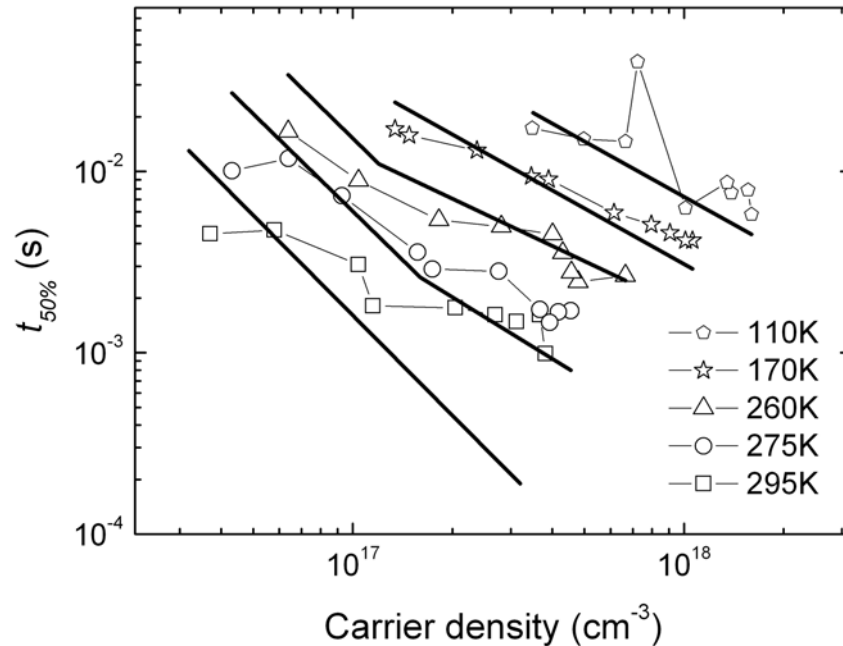


	110	170	260	275	295
Gaussian or exponential	G	G	G	E	E
E_0 (meV)	85	143	30	52	59
σ (meV)	20	20	100	N/A	N/A

General trends as temperature falls

- DoS shallows
- DoS becomes narrower

Recombination fits to the data



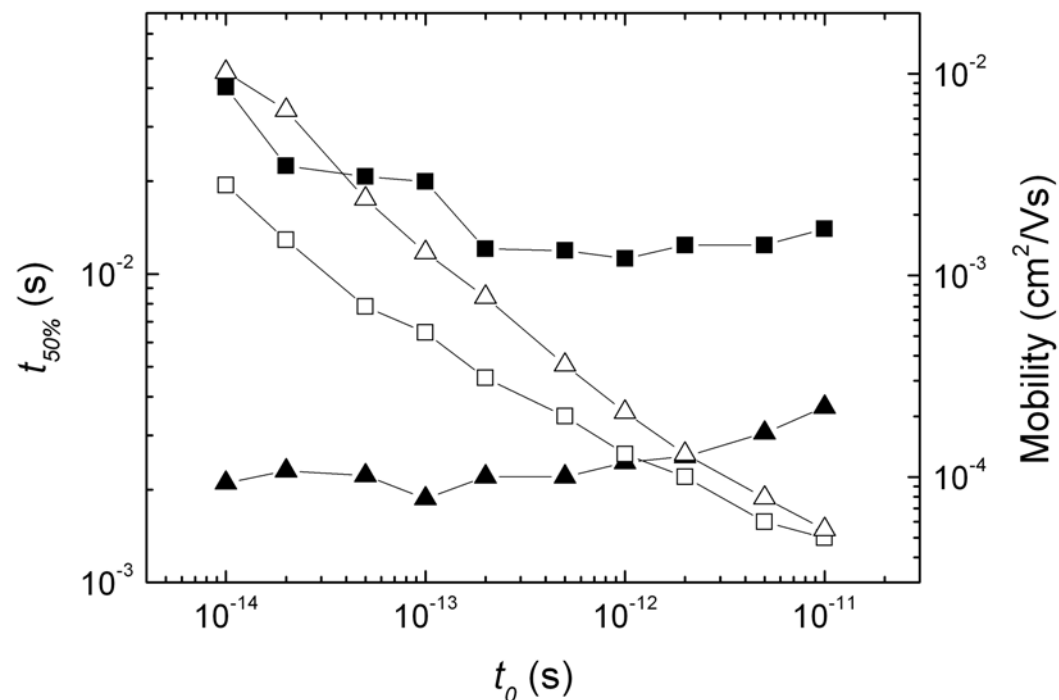
- Use identical DoS as previously
- Only vary k_s
- Good fits with thermally activated k_s

	110K	170K	260K	275K	295K
Gaussian or Exponential	Gaussian	Gaussian	Gaussian	Exponential	Exponential
E_0	85meV	143meV	30meV	52meV	59meV
σ	20meV	20meV	100meV	N/A	N/A
k_s	$6 \times 10^4 \text{s}^{-1}$	$8 \times 10^4 \text{s}^{-1}$	$3 \times 10^7 \text{s}^{-1}$	$4 \times 10^7 \text{s}^{-1}$	10^{10}s^{-1}
$\langle E \rangle$	126meV	170meV	352meV	450meV	500meV

What does this all mean?

- Artificially vary the transport while keeping all other parameters constant

$$t_{i \rightarrow j} = -\ln(r) t_0 \exp(E_i / kT)$$



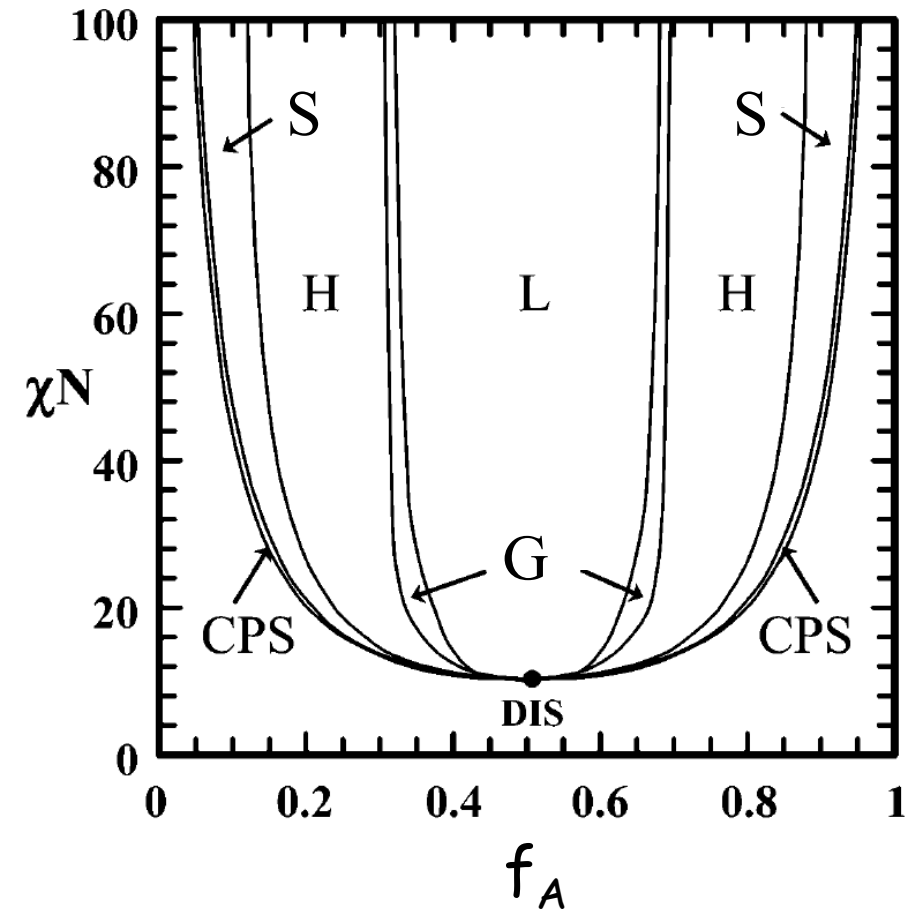
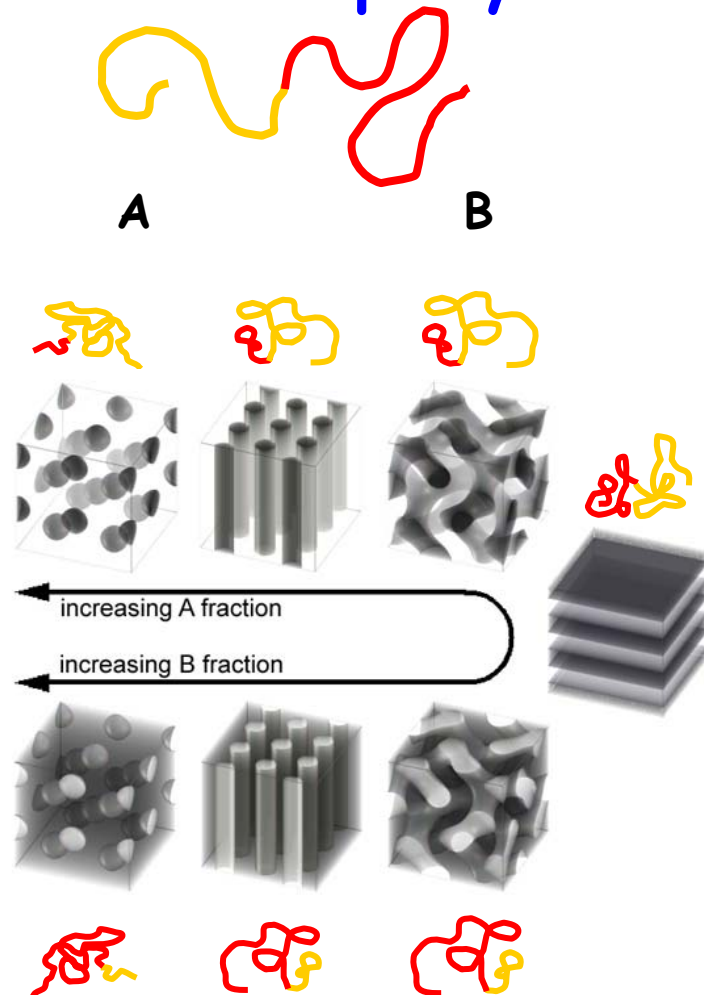
Charge density dependence arises mainly from bi-molecular nature ($\text{rec} \propto n \times p$)

Recombination limited by interfacial recombination process and not transport.

III

TiO₂ electrodes structured
by diblock copolymer
templates:: probing the
structure-function
relationship

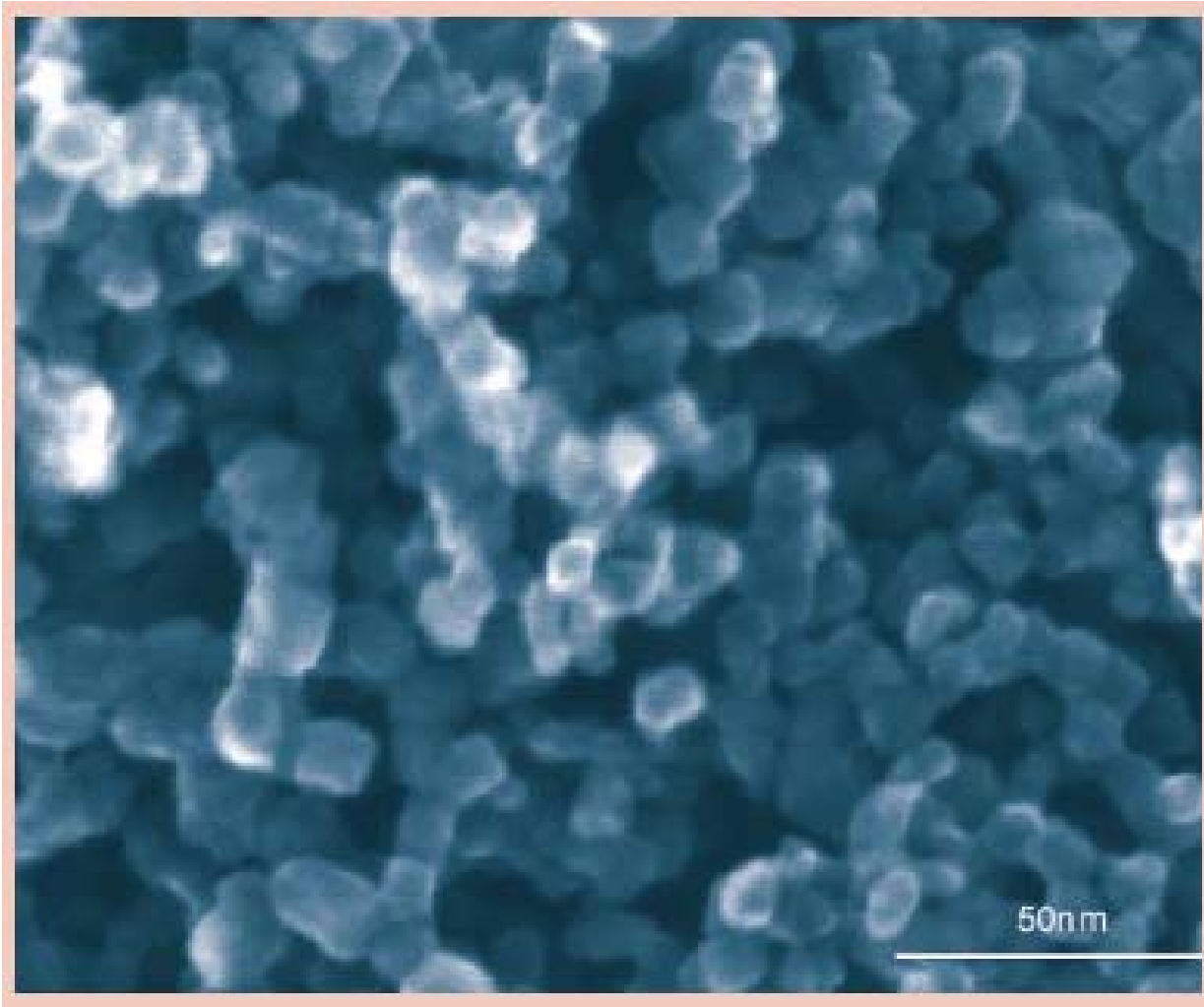
Controlling structure *via* diblock copolymer self-assembly



Images : Mathematical Sciences Research Institute (MSRI) <http://www.msri.org>

Theoretical Phase Diagram: Cochran, E. W. et. al. *Macromolecules*; **2006**; *39*, 2449-2451

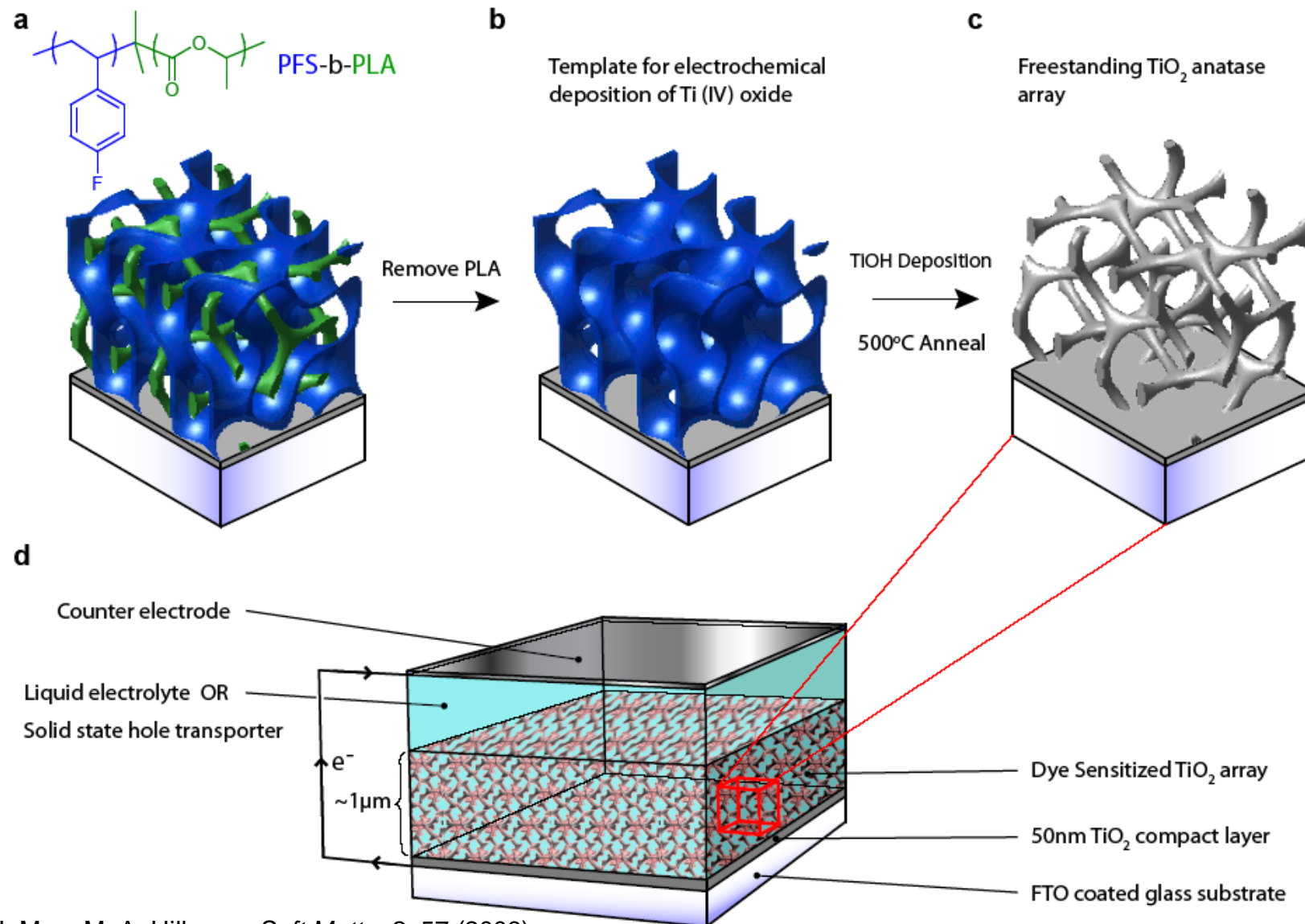
Standard mesoporous titania



Colloidal TiO_2 particles
mixed with polymer to
make paste

Heated, burnt and
sintered at 500degrees

Templating route

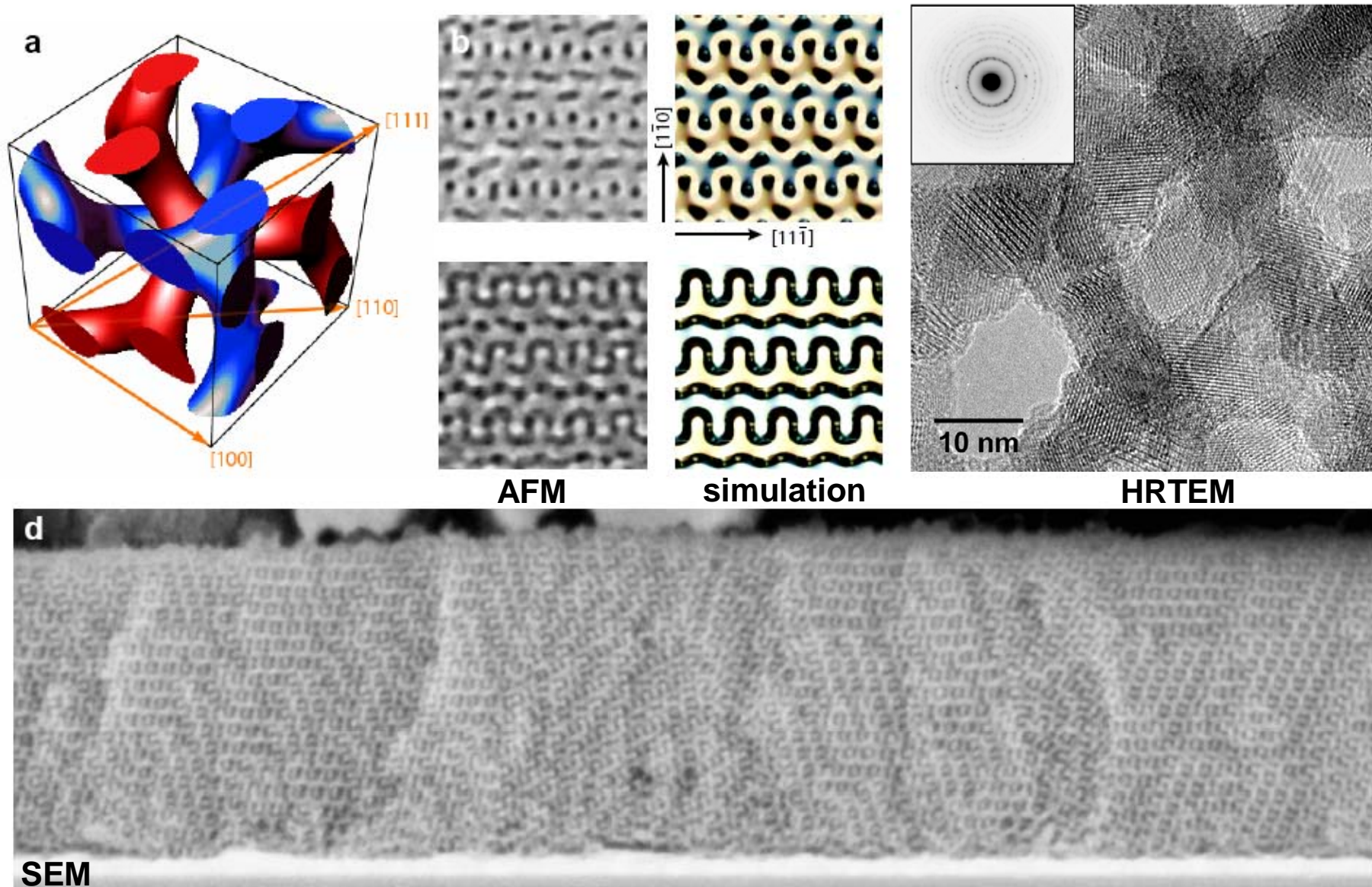


H. Mao, M. A. Hillmyer, *Soft Matter* 2, 57 (2006)

14. G. S. Armatas, M. G. Kanatzidis, *Nature* 441, 1122 (2006). (Germanium)

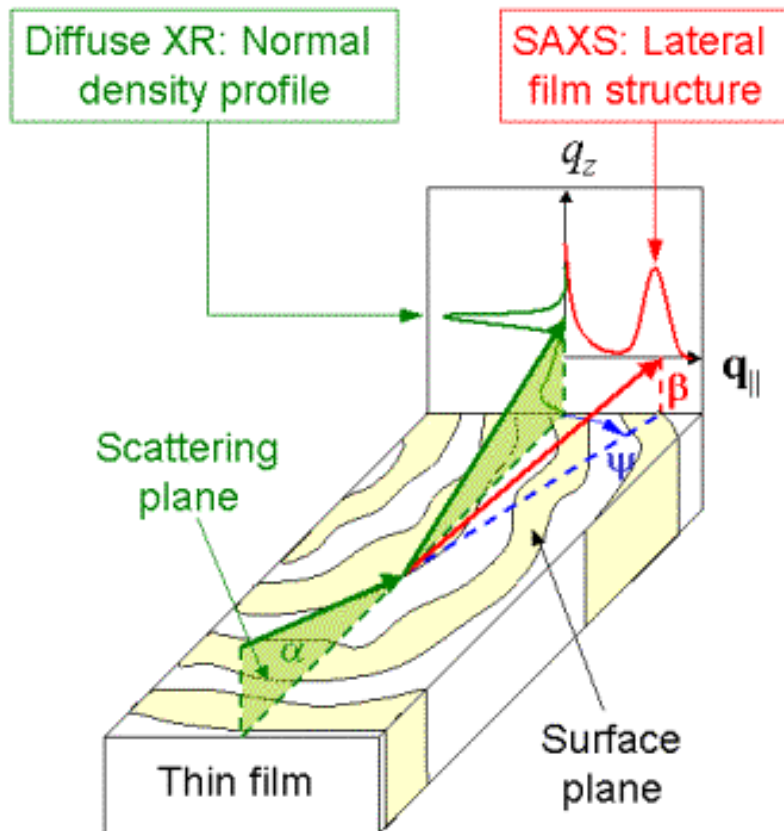
15. V. N. Urade, T. Wei, M. P. Tate, J. D. Kowalski, H. W. Hillhouse, *Chem. Mater.* 19 (2007). (Platinum)

Replicated Gyroid in TiO_2



Other Gyroid systems: G. S. Armatas, M. G. Kanatzidis, *Nature* 441, 1122 (2006). (Germanium)
 V. N. Urade, T. Wei, M. P. Tate, J. D. Kowalski, H. W. Hillhouse, *Chem. Mater.* 19 (2007). (Platinum)

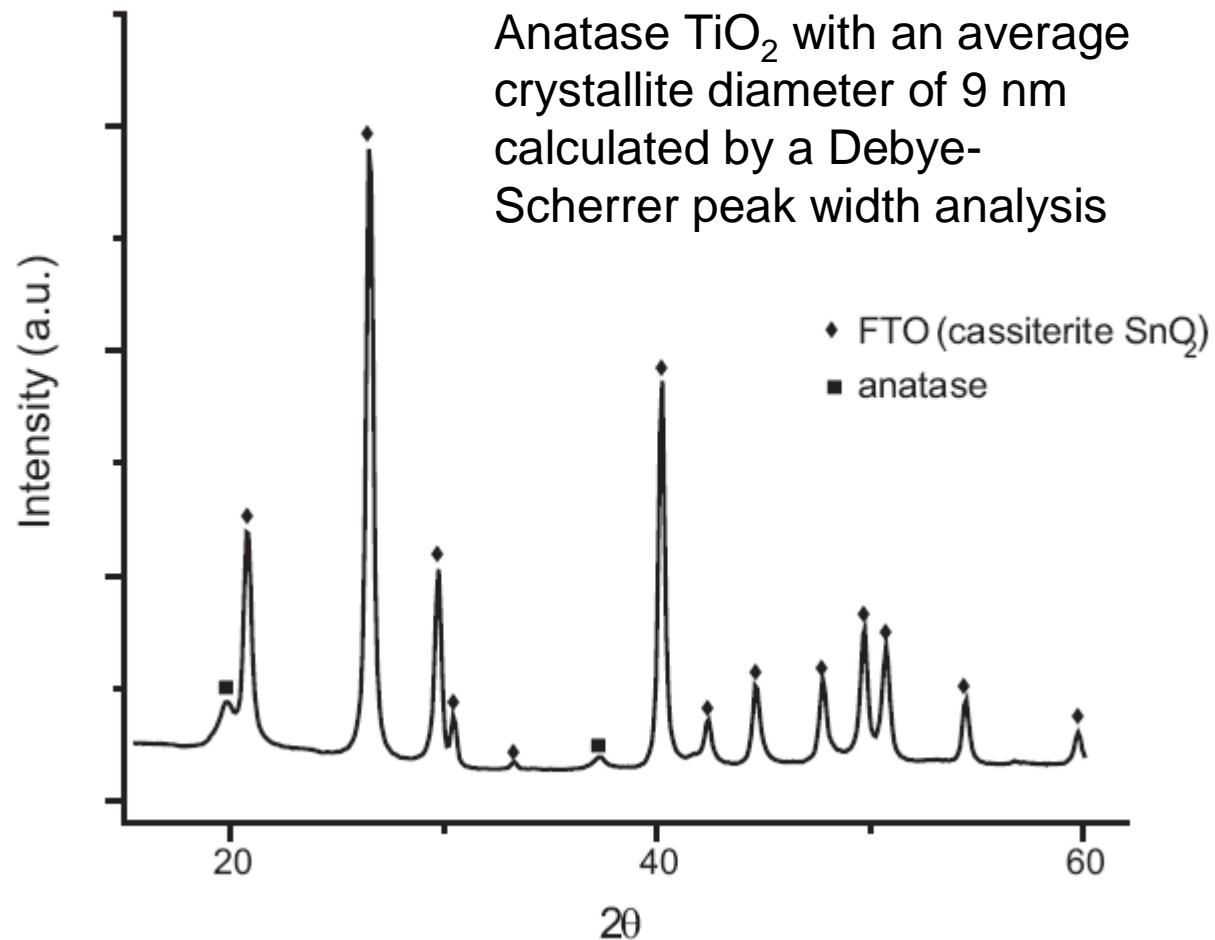
X-ray scattering



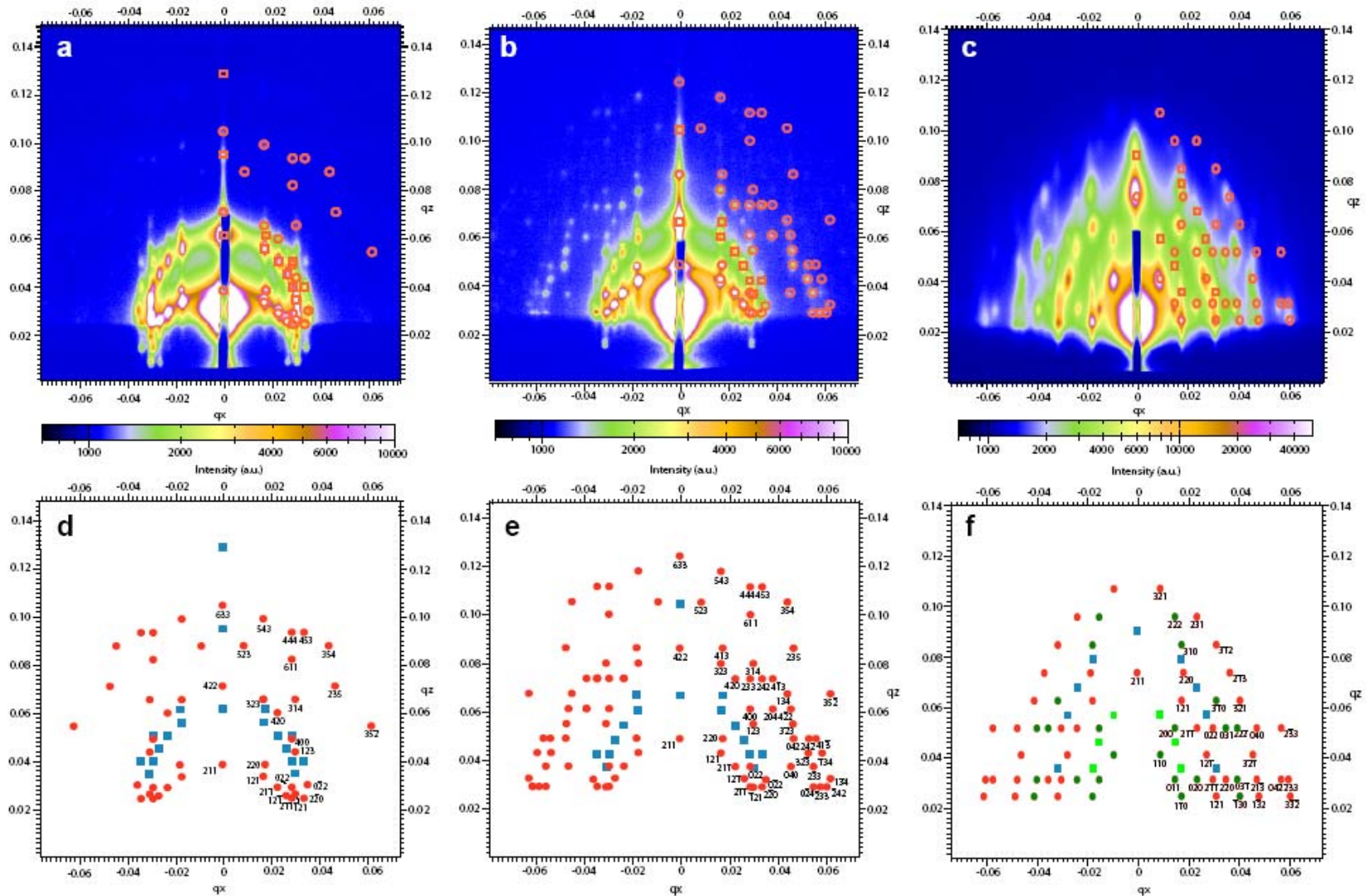
Small angle \rightarrow long range film structure

Wide angle \rightarrow small feature, crystal structure

Grazing incidence wide-angle X-ray scattering (GIWAXS)



Characterisation of the gyroid morphology by GISAXS



voided PFS template
9% z-compression

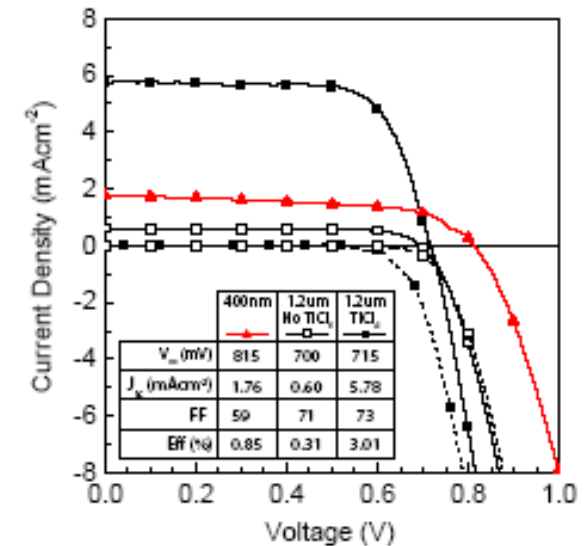
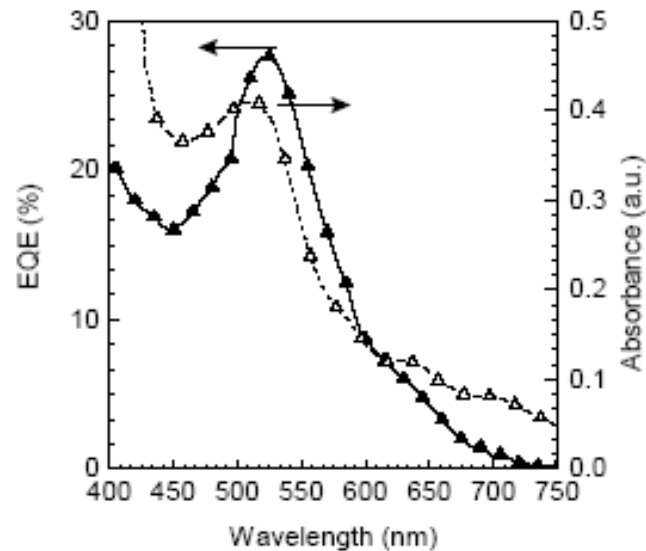
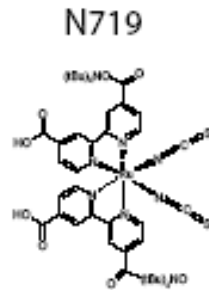
Ti(V) hydroxide
21% z-compression

Titania array
53% z-compression

Solar cell performance

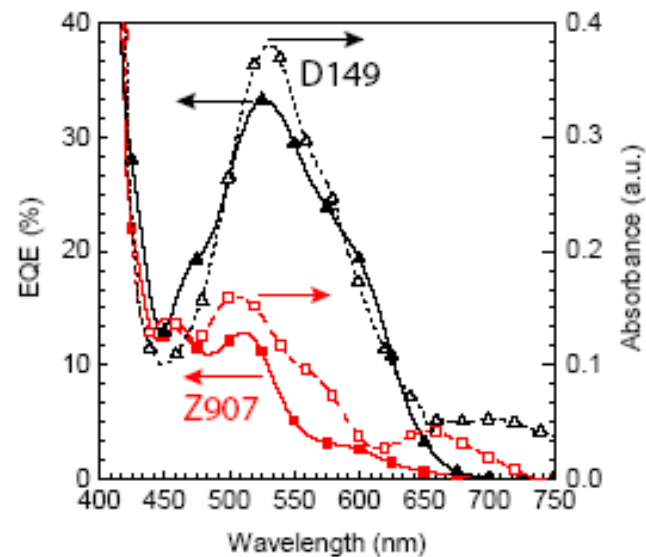
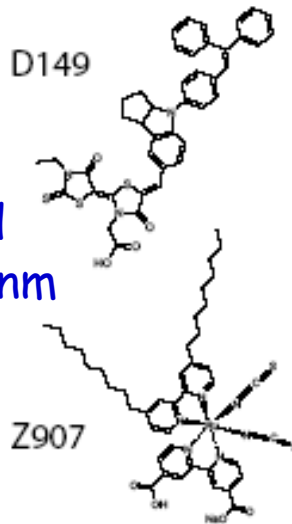
Liquid
1.2 μm

"Robust"
electrolyte

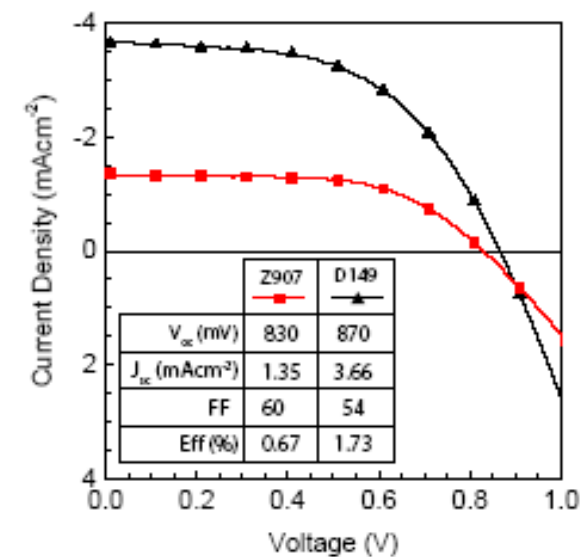


c

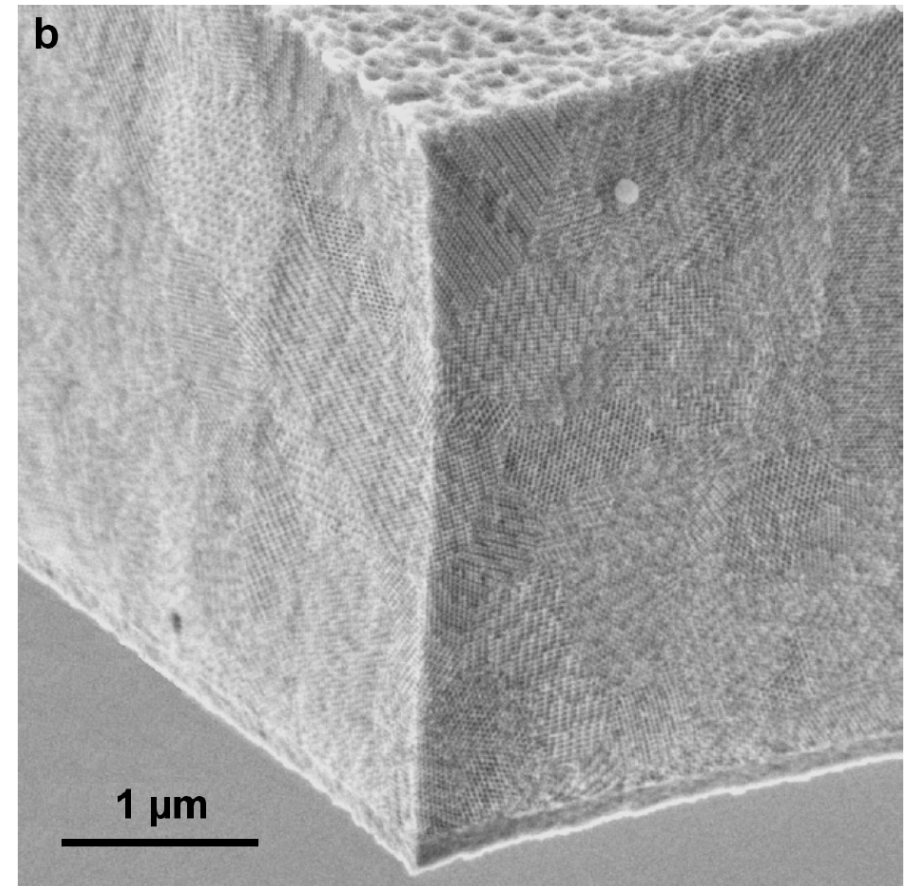
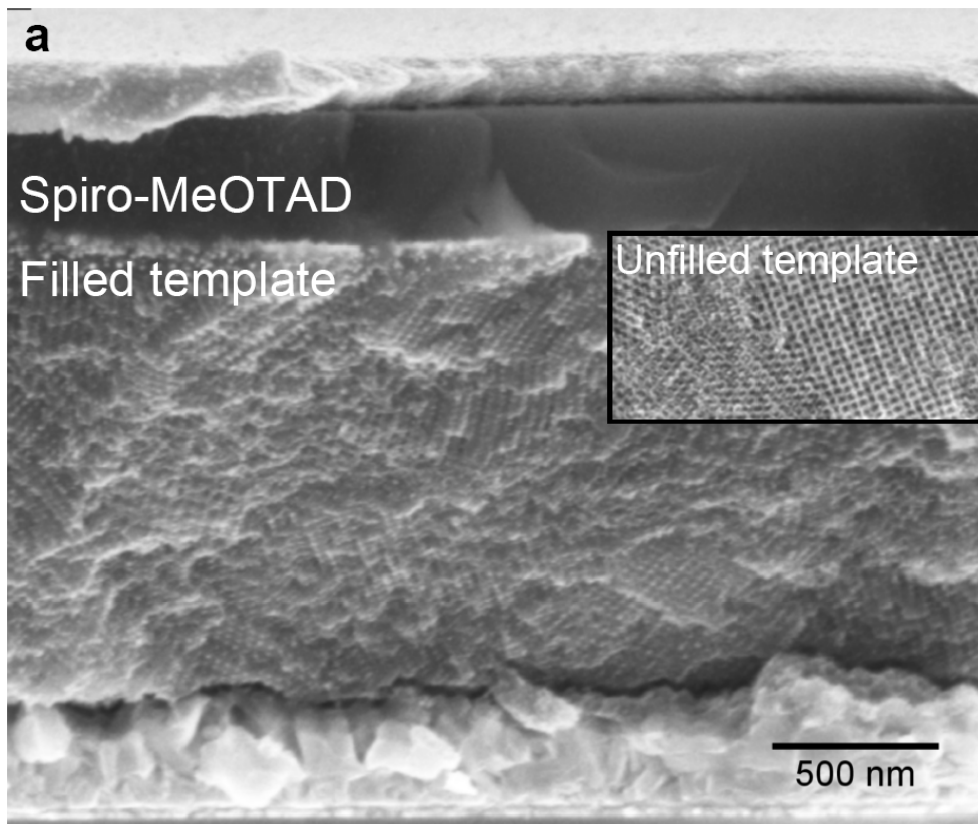
Solid
400 nm



d

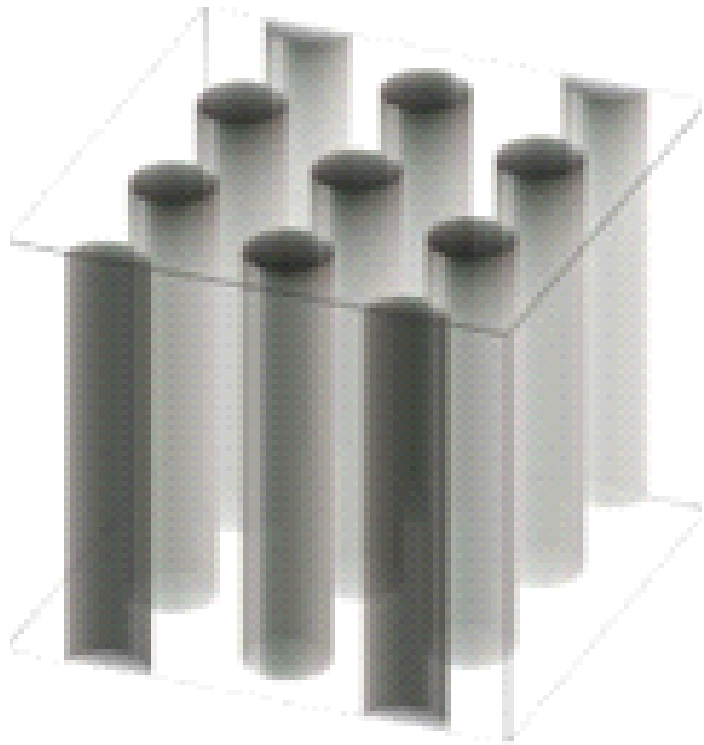


Good pore filling and thick films

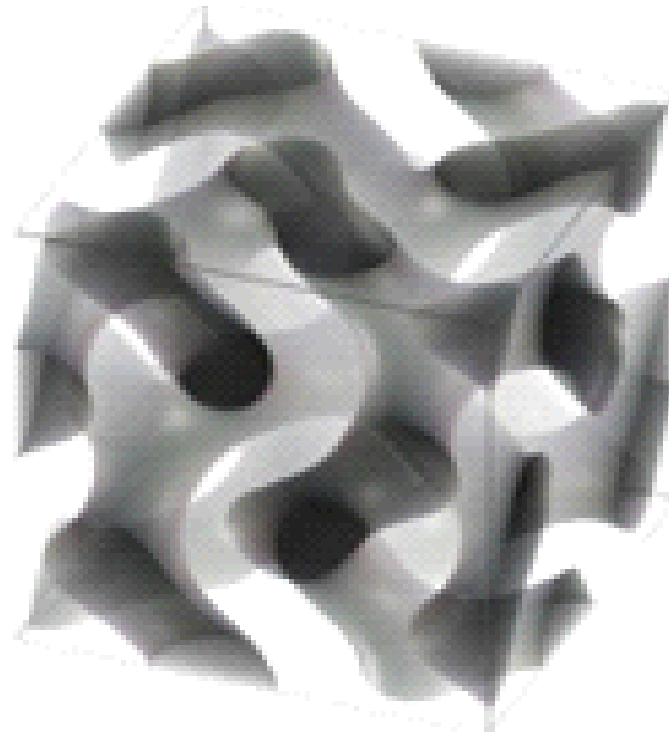


Influence of mesostructure

Wires



Gyroid

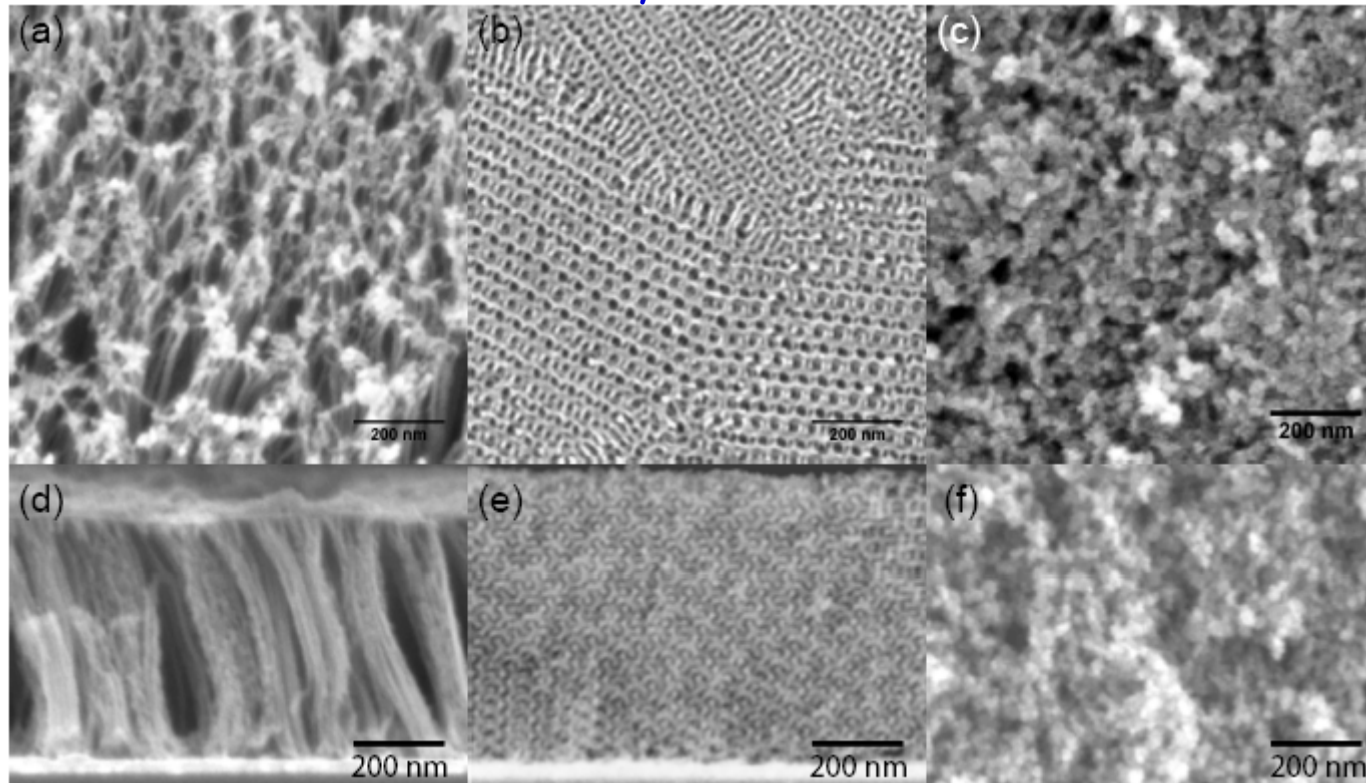


Structure function investigation

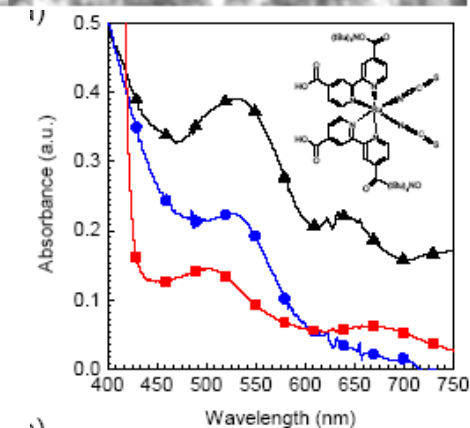
Wires

Gyroid

Particles

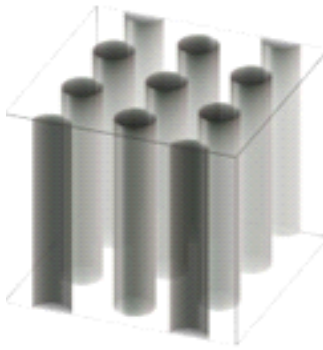


Morphology	RF _{calc} ^a	RF _{meas} ^b	Porosity (%)
Wires	100	60	65
Gyroid	125	130	60
Particles	120	116 ²¹	60

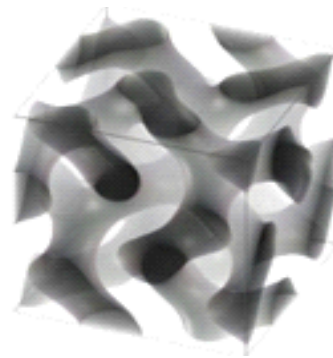


High Resolution TEM

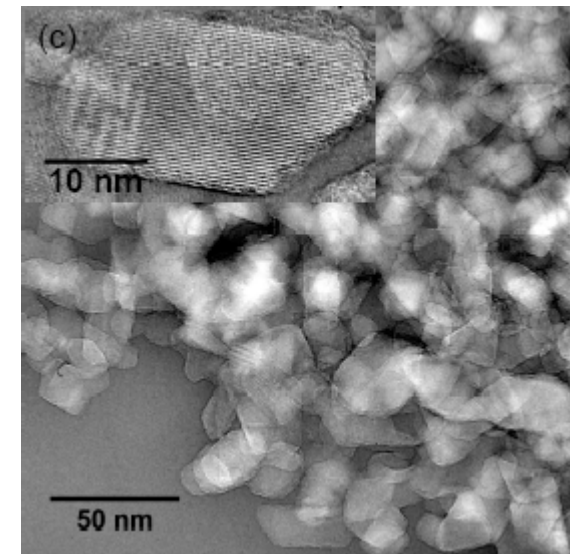
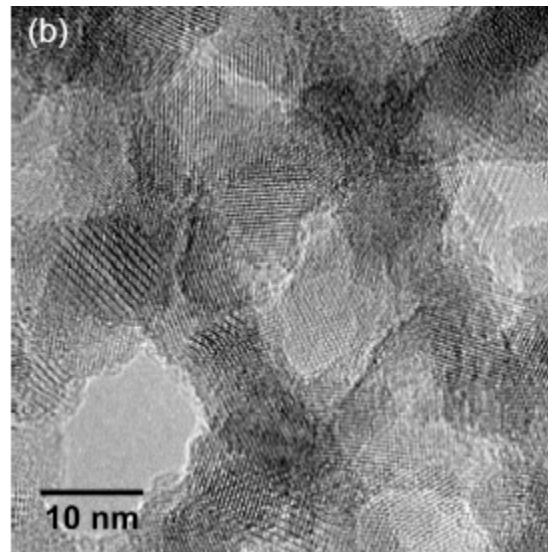
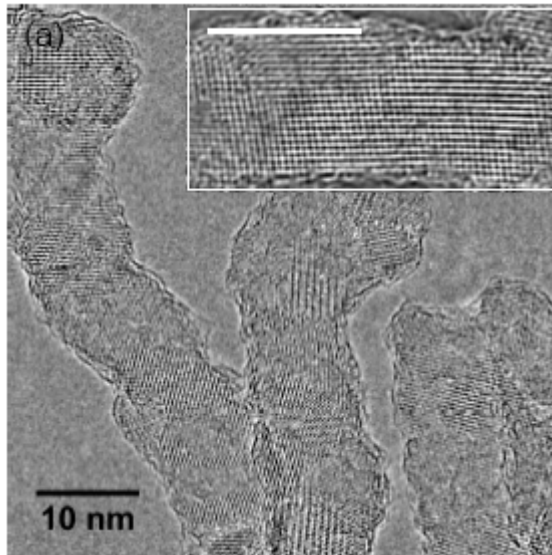
Wires



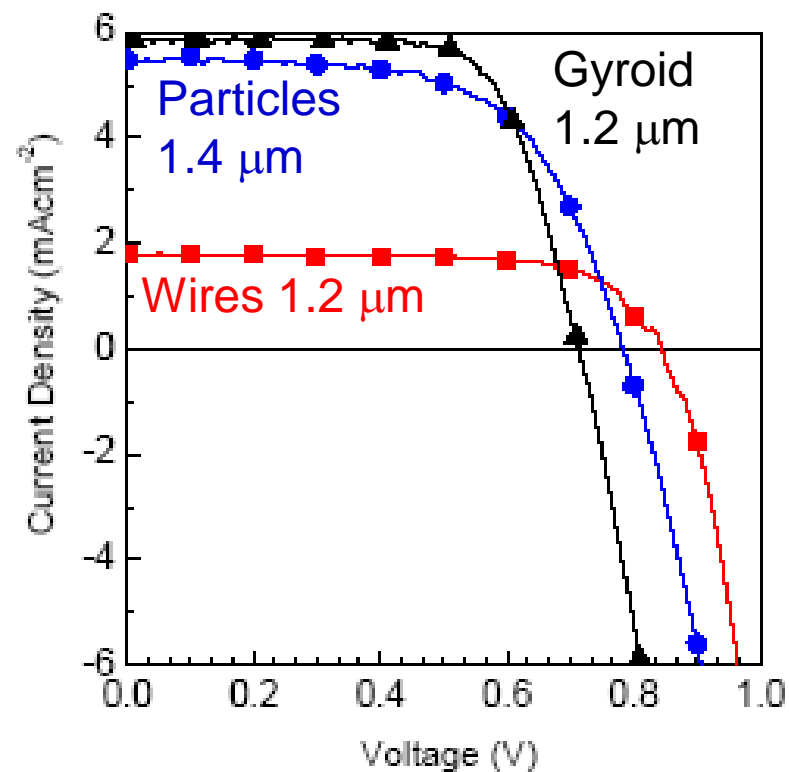
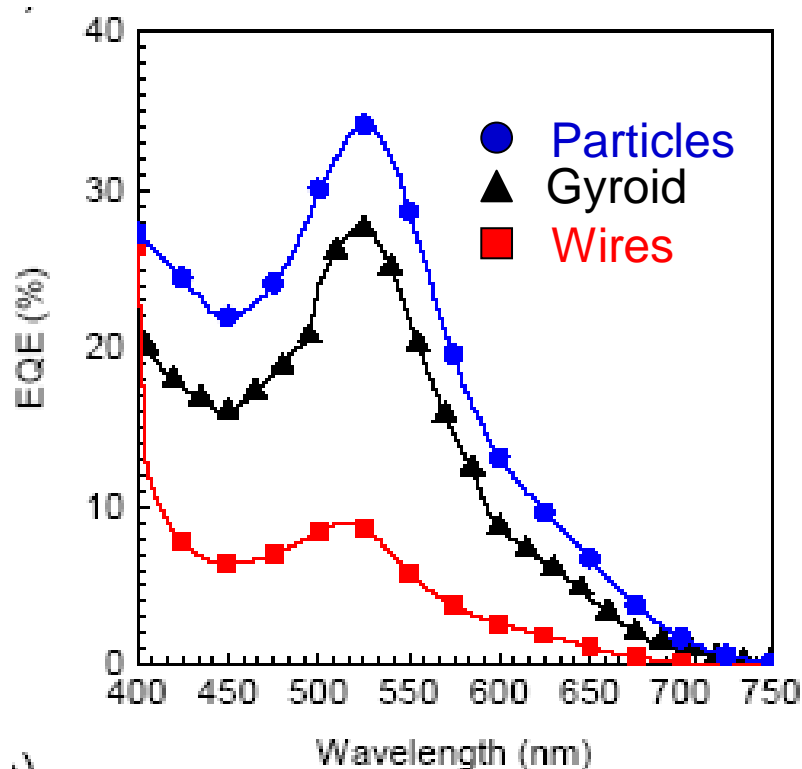
Gyroid



Particles



Solar cell performance (I^-/I_3^-)



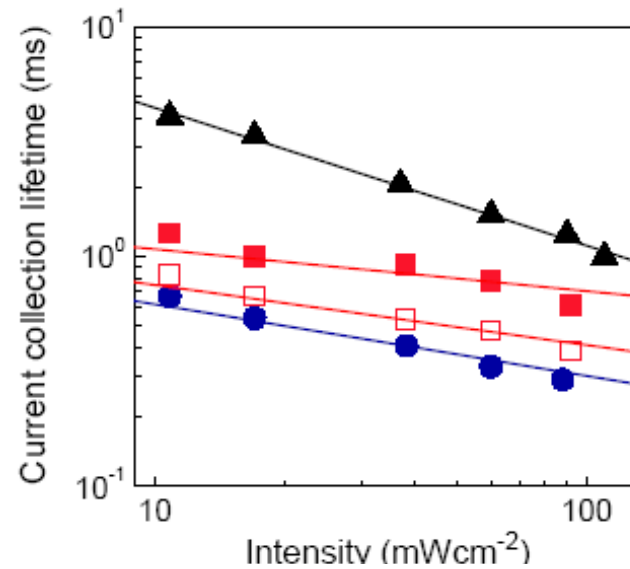
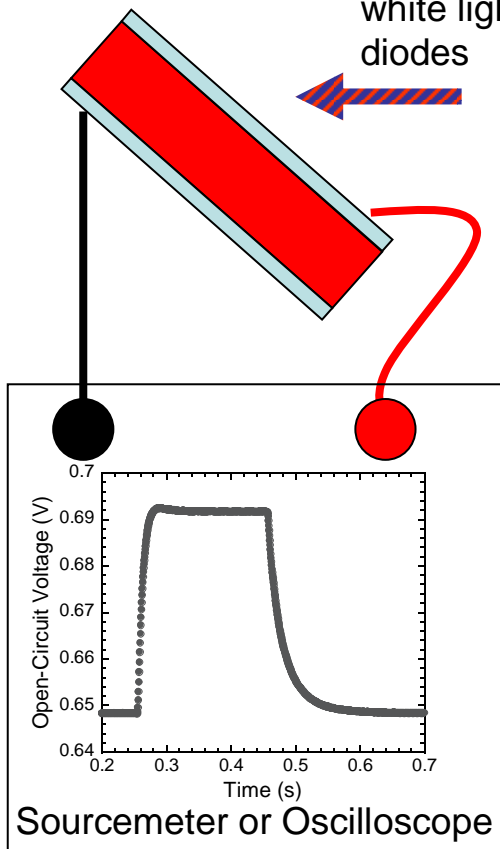
Morphology	J_{SC} (mAcm^{-2})	V_{OC} (mV)	FF (%)	η (%)
Wires	1.79	845	71	1.07
Gyroid	5.83	713	71	2.97
Particles	5.42	785	63	2.67

Charge transport and recombination

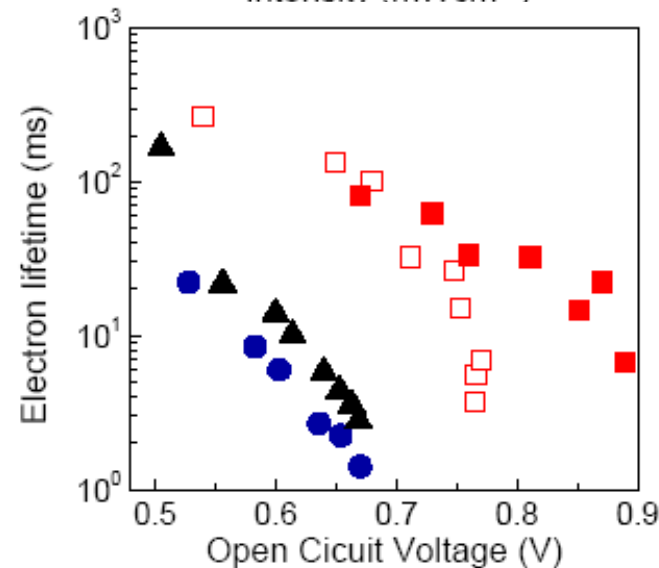
Red light diodes
20 ns rise/fall
time 1ms pulse
width.



white light
diodes



● Particles
▲ Gyroid
■ Wires



summary

- Charge diffusion length 20 μm in (best) SDSCs
- Recombination limits fill factor and open-circuit voltage
- Pore filling primarily limits short-circuit photocurrent
- Large data set for mobility in TiO_2 only possible to fit to MT model if the DoS is allowed to vary with temperature.

Summary

- First realisation of gyroid structured “semiconducting” material, with application in photovoltaics.
- Initial structure-function study
 - Enhanced transport in wires, however lack of structural integrity c.f. self supporting Gyroid

Acknowledgements

EPFL

- Peter Chen
- Ilkay Cesar
- Seigo Ito
- Robin Humphry-Baker
- Shaik Zakeeruddin
- Pascal Comte
- Michael Grätzel

Cambridge:

- Ed Crossland
- Mihaela Nedelcu
- Annamaria Petrozza
- Chris Groves
- Richard Friend
- Ullrich Steiner

Elsewhere:

- Marleen Kamperman
- Caterina Ducati,
- Detlef Smilgies,
- Gilman Toombes,
- Marc Hillmyer
- Sabine Ludwigs
- Ulrich Weisner